

# United States Patent [19]

# Machado et al.

# [54] MINIATURE DISK DRIVE HAVING EMBEDDED SECTOR SERVO WITH SPLIT DATA FIELDS AND AUTOMATIC ON-THE-FLY DATA BLOCK SEQUENCING

- [75] Inventors: Michael G. Machado, Boulder, Colo.; Clifford M. Gold, Fremont, Calif.; Bruce R. Peterson; Daniel E. Barnard, both of San Jose, Calif.; James H. Do, Milpitas, Calif.
- [73] Assignee: Quantum Corporation, Milpitas, Calif.
- [21] Appl. No.: 86,824
- [22] Filed: Jul. 7, 1993

## **Related U.S. Application Data**

- [60] Division of Ser. No. 710,861, Jun. 4, 1991, abandoned, which is a continuation-in-part of Ser. No. 650,791, Feb. 1, 1991, Pat. No. 5,241,546.
- [51] Int. Cl.<sup>6</sup> ...... G06F 13/32
- [52] U.S. Cl. ...... 395/438; 395/310; 395/404;

360/77.08; 360/77.02

#### [56] **References Cited**

### U.S. PATENT DOCUMENTS

3,299,411	1/1967	Capozzi et al 340/172.5
3,771,136	11/1973	Heneghan et al 340/172.5
4,016,603	4/1977	Ottesen 360/135
4,358,826	11/1982	Bodner et al
4,375,069	2/1983	Halvorsen et al 360/49
4,669,004	5/1987	Moon et al
4,811,124	3/1989	Dujari et al 360/49
4,819,153	4/1989	Graham et al 364/200
4,924,427	5/1990	Savage et al 364/900
5,261,058	11/1993	Squires et al 395/275

[11] Patent Number: 5,517,631

# [45] **Date of Patent:** May 14, 1996

## FOREIGN PATENT DOCUMENTS

0126610	11/1984	European Pat. Off
0300264 A3	1/1989	European Pat. Off
0402912 A3	12/1990	European Pat. Off
0471314 A1	2/1992	European Pat. Off

#### OTHER PUBLICATIONS

Worden, "Design Considerations For Dual Density Diskett Controller", *Computer Design*, vol. 17, No. 6, Jun. 1978, pp. 103–110.

"Fault Tolerant Index Detection Pattern For Hard Disk Files", *IBM Tech. Discl. Bull.* vol. 29, No. 12, May 1987, pp. 5350–5351.

Scientific Micro Systems, Data Sheet, OMTI 5000 Data Controller Chips, 1985, four pages.

Cirrus Logic Data Sheet CL–SH350 Integrated Synchronous SCSI Controller, Nov. 1989.

National Semiconductor Data Sheet DP8491 Hard Disk Data Path Electronics Circuit, Sep. 5, 1991.

Silicon Systems Data Sheet SSI 32C452 Storage Controller Jul. 1990.

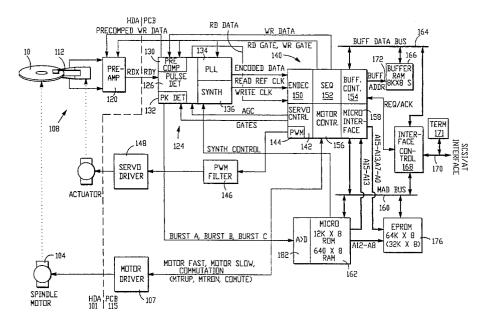
Primary Examiner—Reba I. Elmore Attorney, Agent, or Firm—David B. Harrison

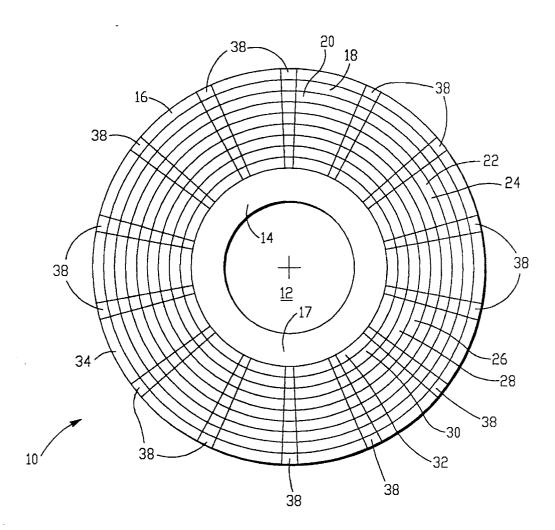
#### Muomey, figeni, or Fum-Bavia B. Hailis

## [57] ABSTRACT

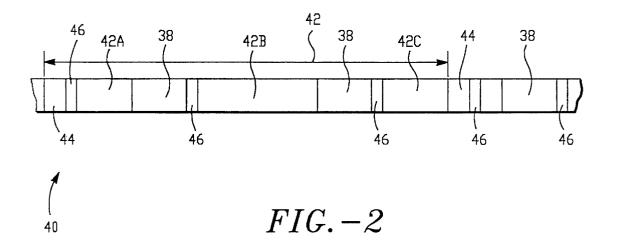
A programmable data sequencer transfers fixed length data blocks between variable length storage segments of a magnetic storage disk and a buffer memory within a data storage device. The data sequencer includes a stack memory for holding user byte count values read from a header field preceding each data sector having variable length split storage segments. Each byte count value indicates respective length of a following variable length storage segment, so that the storage capacity of each segment is dynamically determined by the data sequencer in real time by popping the user byte count value from the stack into a storage segment length counter and by counting down the count value within the segment length counter.

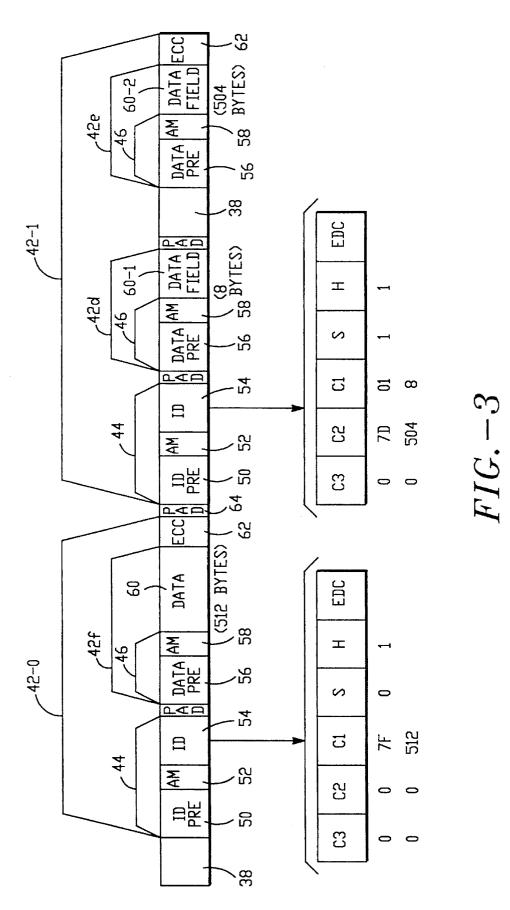
#### 13 Claims, 6 Drawing Sheets



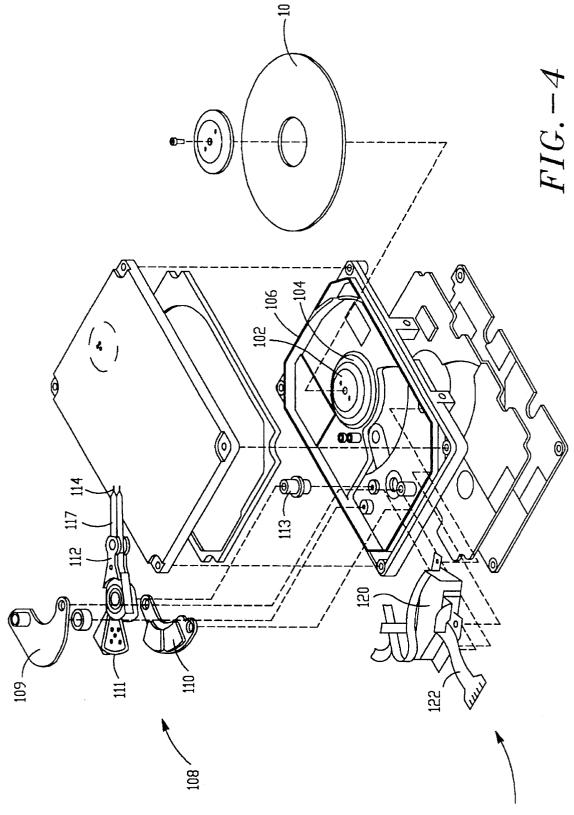


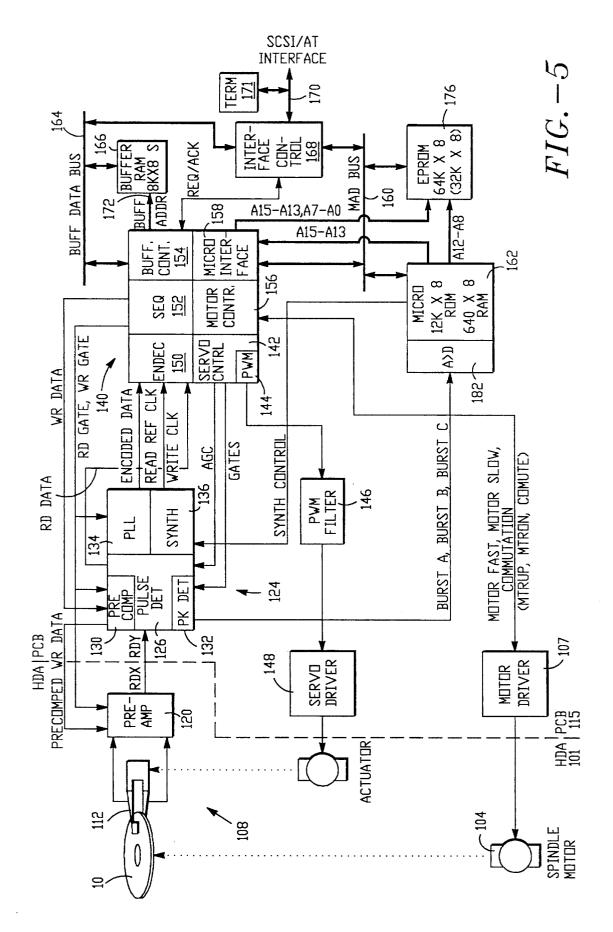
*FIG.* – 1

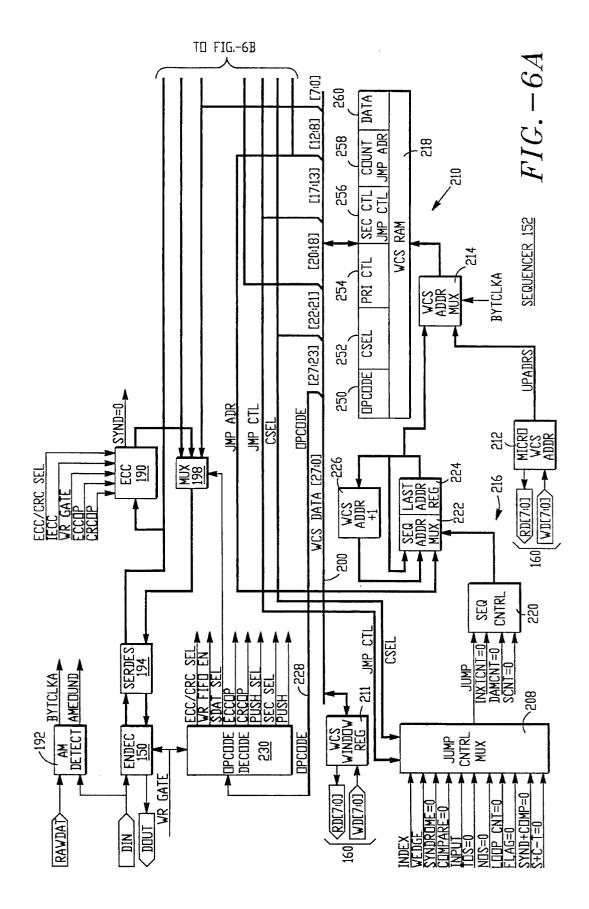


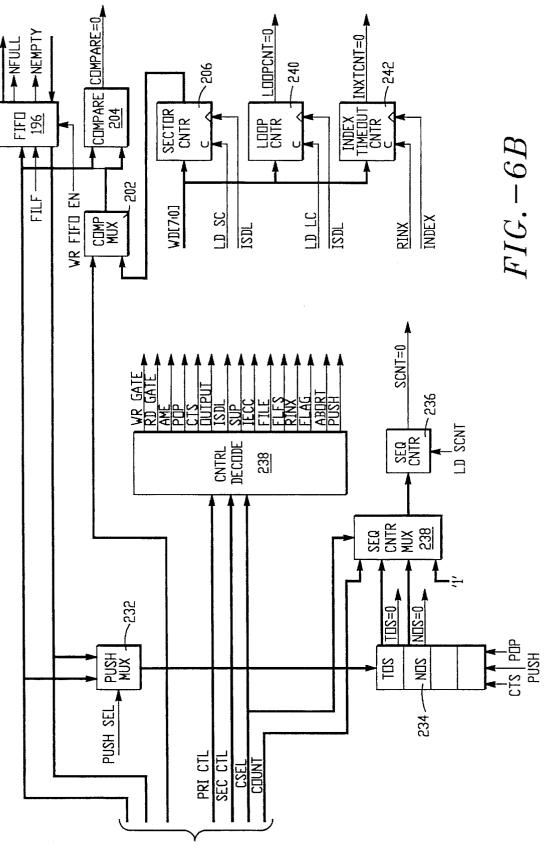


5,517,631









FROM FIG.-6A

# MINIATURE DISK DRIVE HAVING EMBEDDED SECTOR SERVO WITH SPLIT DATA FIELDS AND AUTOMATIC **ON-THE-FLY DATA BLOCK SEQUENCING**

## REFERENCE TO RELATED APPLICATION

The present application is a division of U.S. patent application Ser. No. 07/710,861, filed on Jun. 4, 1991, now abandoned, which is a continuation-in-part of U.S. patent 10application Ser. No. 07/650,791, filed on Feb. 1, 1991, now U.S. Pat. No. 5,241,546.

## REFERENCE TO MICROFICHE APPENDIX

Reference is made to a microfiche appendix accompany-<sup>15</sup> ing the parent patent application, U.S. patent application Ser. No. 07/710,861, filed on Jun. 4, 1991, now abandoned, containing microcontroller routine program listings and detailed schematic circuit diagrams of elements of a disk drive and data sequencer embodying principles of the  $^{\rm 20}$ present invention.

## FIELD OF THE INVENTION

The present invention relates to a data sequencer for high 25 capacity, high performance fixed disk drive data storage subsystems. More particularly, the present invention relates to a data sequencer for a fixed disk drive supporting an embedded sector servo arrangement wherein the servo sectors split up the data fields and wherein the sequencer 30 provides automatic data block sequencing with dual function opcodes for reading and writing data blocks in real time without substantial intervention of a supervisory microcontroller.

## BACKGROUND OF THE INVENTION

Disk drives, particularly fixed disk drives, are valued on the basis of several factors including size (i.e. sometimes referred to as "form factor"), data storage capacity, random 40 access times between data fields located in disparate concentric data tracks of the storage disk (i.e. sometimes referred to as "access time" or "average access time"), cost per byte stored, and useful life (i.e. sometimes rated as "mean time between failures").

When data tracks are arranged as concentric circles on a circular storage surface, outer tracks or circles are longer and therefore have more useful magnetic storage domains than inner tracks. Also, when storage disks are rotated at a constant angular velocity, the data transducer head "flies" at a faster and somewhat higher altitude above outer storage tracks where relative head to disk velocity is greater, than inner tracks.

One known way to increase data storage capacity is to divide the data storage surface into radial zones of tracks, 55 and to optimize data transfer rate to the smallest track (innermost track) within each particular zone. This approach is sometimes called "zoned data recording". The number of data sectors or fields within each track typically may vary from zone to zone. In order to switch from zone to zone, it  $_{60}$ is necessary for the disk drive to adapt itself in real time to the number of data sectors and to the new data rate.

Other known ways to increase data storage capacity include varying disk rotation in function of radial position of the data transducer head while maintaining data transfer rate 65 substantially constant, as is the case with optical disk technology; and, varying data transfer rate with each track in

function of the radial position of the head, while maintaining disk rotation constant, as is the typical case with fixed disk, "flying head" technology.

Issues confronting the designer of a disk drive include head positioning, and data block transfer. Head positioning is typically carried out by a head positioner servo mechanism and involves "track seeking operations" for moving the data transducer head from a departure track to a destination track throughout the radial extent of the storage area of the disk; and, "track following operations" for causing the data transducer head to follow precisely a particular data track during data block reading/writing operations. In order to provide precise head positioning, during both seeking and following, some servo information must be provided to the head positioner servo. This information may be contained on a special data surface written exclusively with servo information, (called a "dedicated servo surface"), or it may be externally supplied as by an optical encoder coupled to the head positioner arm, or it may be supplied from servo information interspersed or "embedded" among the data fields within each data track. One other approach worth mentioning is provided by the open loop stepper motor head positioner servo wherein positional stability of the head at each selected data track location is provided by electromagnetic detents of the stepper motor.

When servo information is embedded on a data surface having zoned data recording, complications arise in reliably providing robust servo head position information. There must be sufficient embedded information to provide stability to the servo loop and to provide position feedback during high speed portions of track seeking operations, so that velocity or position profiles may be adjusted, based on present head velocity or position at the time of the sample. If the servo information is recorded at the same data rate, and in positional relationship with the data blocks, as has been conventionally employed, the servo architecture is complex in the sense of having to switch data rate and servo position, as zones are crossed over. One example of data zones with switched servo sector locations is provided by the disclosure of Ottesen U.S. Pat. No. 4,016,603, for example. If the servo information is regularly spaced radially across the data storage surface and splits at least some of the data fields into segments, complications arise in reading each split data field as a single data block without error. Also, the disk rotational velocity must be monitored and carefully maintained at a predetermined constant angular velocity.

Data fields are conventionally managed by a data sequencer. One example of a data sequencer is to be found in commonly assigned U.S. Pat. No. 4,819,153, the disclosure thereof being incorporated herein by reference. The data sequencer may include an encoder/decoder for transforming non-return-to-zero (NRZ) data into a coded data format, such as a three to two 1,7 run-length-limited (RLL) code in order to achieve compression of data relative to flux transition density on the data surface. (1,7 RLL coding is based on three cede bits or groups for two unencoded data bits, but results in a four to three overall data compaction rate and therefore permits more data to be recorded on the disk per the number of flux transitions that may be contained within the magnetic storage domains.)

A data sequencer conventionally performs the task of decoding data sector overhead information in order to locate a desired storage location, and to obtain information relating to the correctness or validity of data read back from the storage location. Typically implemented as a state machine, a data sequencer conventionally monitors incoming data flow to locate a data identification (ID) preamble field, a data

35

55

ID address mark, a sector ID field, the data field itself, and usually some small number of error correction syndrome bytes appended to the end of the data field. The sequencer causes appropriate action to be taken when each of the fields is located. For example, if a data block from the data field 5 of a particular track and sector is being sought, the sequencer compares incoming sector ID field information with the sought-after sector information stored in a register. When a positive comparison occurs, the sequencer causes the bytes read from the data field via a data transducer head and a read 10 channel to be sent into a block buffer memory, and the error correction syndrome remainder bytes to be checked. If there are no detected errors in the data bytes as determined by analyzing the error correction code (ECC) remainder bytes, the block is then sent from the buffer memory to the host 15 computer via a suitable interface, such as Small Computer System Interface (SCSI).

In the disk drive described in a commonly assigned U.S. Pat. No. 4,669,004, each sector was handled individually in response to specific input from the supervisory microcon- 20 troller. The disclosure of this patent is incorporated herein by reference. As a particular sector was read, the microcontroller would inform the sequencer whether or not to read the next data sector. This microcontroller intervention occurred for every sector.

In a later design, of which the disclosure found in commonly assigned U.S. Pat. No. 5,005,089, is incorporated herein by reference, a programmable sector counter was preset by the microcontroller to a desired sector count, and 30 the sequencer then processed sectors sequentially until the count in the sector counter was reached. The disk drive examples found in the referenced '004 and '153 patents did not include the complication of zoned data recording and split data fields, and the '089 patent did not include embedded servo sectors. Positioner stability in the '089 disk drive 35 example was provided by an optical encoder coupled between a rotary head positioner and the drive base, as was the case of the disk drive example described in the referenced '153 patent.

40 Heretofore, while split data recording schemes have been proposed in the prior art, recent proposals have typically tasked the data microcontroller with the responsibility for managing each split data field layout in real time, leading to a tremendous level of bus traffic between the microcontroller 45 and the data sequencer during data read and write operations, and precluding the microcontroller from performing other very useful tasks, such as those related to head position servo supervision, error correction, command and status exchanges with the host computer over the interface bus 50 structure, to cite a few examples. These prior approaches have therefore required a separate data transfer microprocessor, meaning that at least two microprocessors were required to implement an overall disk drive architecture.

## SUMMARY OF THE INVENTION WITH **OBJECTS**

A general object of the present invention is to provide a data sequencer for a data storage device which overcomes 60 limitations and drawbacks of the prior art.

A more specific object of the present invention is to provide a data sequencer for a disk drive employing zoned data recording having data fields split into segments by intervening embedded servo sectors and wherein the data 65 sequencer provides for automatic sequencing of data blocks during writing data to, and reading data from, the split data

fields, in a manner which overcomes limitations and drawbacks of the prior art approaches.

Another specific object of the present invention is to provide a unique identification field for each data sector which supports directly automatic data sequencing through each split data field without direct microprocessor intervention.

Another specific object of the present invention is to provide an improved data sequencer for a disk drive which autonomously sequences through split data fields without requiring constant intervention by a microcontroller element to decode the particular format of each split data field, thereby freeing the microcontroller to perform other useful tasks.

A further specific object of the present invention is to provide a data sequencer which includes a count stack for holding counts representing lengths of split data fields.

One more specific object of the present invention is to provide a data sequencer which can read and assemble data blocks from split data fields read from the disk, and write split data fields to the disk without any reprogramming of the sequencer between data block read and write operations.

Yet another specific object of the present invention is to provide a plurality of control fields within a writeable control word for a control state of a data sequencer such that two independent control functions may be performed within the state: either two primary control functions, or a primary and a secondary control function.

A still further specific object of the present invention, a data sequencer is provided which includes a test for zero logic tree which employs fewer gates than heretofore for testing an ECC syndrome remainder value.

One more specific object of the present invention is to provide a data storage disk of a disk drive with a unique split field data and embedded servo sector pattern following a predetermined zoned data track arrangement.

One facet of the present invention is found in a data storage pattern for a disk drive including a storage disk rotating at substantially constant angular velocity and having at least one storage surface defining a multiplicity of concentric data tracks, and a data transducer head positionable at each of the tracks by a head positioning mechanism operating within a digital servo loop. The data storage pattern comprises a series of circumferentially spaced apart, radially extending servo sectors, each servo sector being prerecorded with flux transition patterns defining a servo address mark, a servo sector identification number and servo centerline information, the transition patterns defining the sector identification number and the servo centerline information being resolvable by the disk drive into digital numbers representing head position relative to a said concentric track containing the particular sector. The data tracks are grouped into a plurality of concentric track zones, each zone having a data transfer rate related to radial offset of said zone from a center of rotation of the disk. Each track within a zone is soft-formatted into a predetermined number of data sectors of predetermined user data block storage length. At least some of said sectors are interrupted by at least one of the servo sectors and thereby divided into data segments. Each data sector has a data sector identification field including a plurality of user byte count values indicating the user data storage capacity of each segment of the sector. The count values may therefore be read by a data sequencer the disk drive on-the-fly in order to read a user data block from, and to write a user data block to, the segments.

In one aspect of this facet of the invention, each segment of a data sector includes a preamble field including an

address mark, and each said data sector which is divided into plural segments by at least one servo sector includes a data sector identification field as a preamble of a first segment, and a subsequent segment includes a data preamble including a data segment address mark. The data segment address mark is preferably different than the address mark contained within the data sector identification field.

In another aspect of this facet of the invention, the preamble field includes a predetermined sync pattern for enabling a phase locked loop within a data separator of said <sup>10</sup> disk drive to resolve the data transfer rate of the zone of the track containing the particular field, the address mark, an identification field including said count values, a sector and head identifier field for enabling the data sequencer to resolve the particular sector location among the multiple data sectors, and an error detection field for enabling an error correction circuit of the data sequencer to verify correctness of the values contained within the preamble field.

In a further aspect of this facet of the invention, the data transfer rate for the information set forth in the servo sectors <sup>20</sup> is maintained at a fixed rate throughout the radial extent of said storage surface. Also, a predetermined one of the servo sectors preferably contains a prerecorded index pattern indicating a once per revolution index marker for the disk.

In one facet of the invention a programmable data 25 sequencer state machine is provided for a disk drive comprising at least one storage disk rotating at substantially constant angular velocity and having at least one storage surface defining a multiplicity of concentric data tracks. The disk drive includes a data transducer head positionable at 30 each of the tracks by a head positioning mechanism operating within a digital servo loop including a programmed digital microcontroller. The programmable data sequencer comprises a writeable control store including a random access memory area directly addressable by the programmed 35 digital microcontroller for writing sequences of control patterns, there being most preferably a single sequence written for controlling states of the programmable data sequencer during both data read and data write operations to and from the disk surface and a buffer memory. The control  $_{40}$ patterns preferably include an opcode field control pattern, a count select field control pattern, a control field control pattern, a jump field control pattern, a count field control pattern, and a data field control pattern. The data sequencer thus includes an opcode decoder for decoding values com-45 prising an opcode of a said sequence, a jump field decoder for decoding values comprising at least one of a count select field control pattern and a jump field control pattern, a control field decoder for decoding the control field control pattern, a counter responsive to the count field control 50 pattern, and a data decoder responsive to the data field control pattern.

As one aspect of this facet of the invention, the data storage disk defines a series of circumferentially spaced apart, radially extending servo sectors, each servo sector 55 being prerecorded with flux transition patterns defining a servo address mark, a servo sector identification number and servo centerline information, the transition patterns defining the sector identification number and the servo centerline information being resolvable by the disk drive into digital 60 numbers representing head position relative to a particular concentric track containing the sector. The tracks are grouped into a plurality of concentric track zones, each zone having a data transfer rate related to radial offset of said zone from a center of rotation of the disk. Each said track within 65 a zone is soft-formatted into a predetermined number of data sectors of predetermined user data block storage length. At

least some of the data sectors are interrupted by at least one of the servo sectors and are thereby divided into data segments. Each data sector has a data sector identification field including a plurality of user byte count values indicating the user data storage capacity of the particular segment thereof, whereby the count values may be read and processed by the data sequencer on-the-fly in order to assemble a user data block from the segments during a data read operation, and to disassemble a user data block into the segments during a data write operation. In this aspect, the programmable data sequencer state machine further comprises a count stack for storing the user byte count values, and a loadable sector segment counter for receiving sequentially from the count stack each one of the user byte count values for decoding on-the-fly the length of each said segment.

As a further aspect of this facet of the invention the programmable data sequencer state machine comprises a loadable sector counter directly loadable by the programmed microcontroller. The sector counter is responsive to a data clock for counting a preset number of data bytes comprising a data sector. A loadable loop counter is directly loadable by the programmed microcontroller and responds to the data clock for counting a present number of data byte clock periods corresponding to a loop established within sequences of the control patterns. A control field decoder is provided for decoding the control field control pattern and generating the data clock for clocking the sector counter and the loop counter.

As another facet of the present invention, a programmable data sequencer is provided for controlling transfer of fixed length data blocks between variable length storage locations of a storage medium and a buffer memory within a data storage device. The data sequencer includes

a writeable control store including a random access memory directly addressable by a programmed digital microcontroller of the data storage device for writing sequences of control patterns, there being dual function control patterns such that a single sequence of control patterns may be written for controlling states of the programmable data sequencer during both data read operations and data write operations to and from the storage medium and the buffer memory,

a control pattern decoder for decoding the control patterns into functional values for controlling operations within the data sequencer, and

a stack memory for holding user byte count values indicating respective lengths of said variable length storage locations so that the storage capacity of each said storage location is determined by the data sequencer automatically as a user byte count value associated with a particular variable length storage location is provided at the stack memory.

As a further facet of the present invention, a method is provided for controlling transfer of fixed length data blocks between variable length storage locations of a storage medium such as a rotating disk and a buffer memory of a data storage device such as a disk drive. In this facet of the invention, the method comprises the steps of:

writing sequences of control patterns from a programmed digital microcontroller of the device directly to a writeable control store of a data sequencer of the device,

decoding the control patterns into functional values for controlling operations within the data sequencer,

transferring user byte count values indicating respective lengths of segments of the variable length storage locations

from a data header of one of the storage locations directly into a byte count values stack of the data sequencer as the data header is read by a data transducer of the device,

automatically transferring each user byte count value to a byte counter of the data sequencer so that the storage 5 capacity of each said segment is determined by the sequencer automatically by the value held in the byte counter.

As another facet of the present invention, a method is provided for controlling transfer of data blocks between 10 storage locations of a storage medium and a buffer memory of a data storage device. In this facet, the method comprises the steps of:

writing sequences of control patterns from a programmed 15 digital microcontroller of the device directly to a writeable control store of a data sequencer of the device, there being dual function control patterns such that a single sequence of control patterns may be written for controlling states of the programmable data sequencer during both data read opera-20 tions and data write operations to and from the storage medium and the buffer memory, and

decoding the control patterns into functional values for controlling operations within the data sequencer during both data read operations and data write operations without 25 intervention by the programmed digital microcontroller.

These and other objects, advantages, aspects, facets and features of the present invention will be more fully understood and appreciated by those skilled in the art upon consideration of the following detailed description of a 30 preferred embodiment, presented in conjunction with the accompanying drawings.

## BRIEF DESCRIPTION OF THE DRAWINGS

In the Drawings:

FIG. 1 is a plan view of a disk data storage surface including data track zones and radially/circumferentially aligned embedded servo sectors in accordance with the principles of the present invention.

40 FIG. 2 is a graph of a portion of a data track showing a data field being split into segments by recurrent servo sectors. ID and data headers for the data segments include fault tolerant address marks in accordance with principles of the present invention. While the FIG. 2 graph is a rectilinear 45 depiction, within disk drives, the tracks are typically concentric, and a truer representation would show the FIG. 2 segment as an arc segment of a circular track pattern.

FIG. 3 is a more detailed view of the FIG. 2 data track portion.

FIG. 4 is an exploded isometric view of a submicro-Winchester fixed disk drive head and disk assembly, incorporating principles of the present invention.

FIG. 5 is a detailed block diagram of an electrical control system for controlling operation of the FIG. 4 head and disk 55 assembly and incorporating principles of the present invention.

FIGS. 6A and 6B are a detailed block diagram of a data sequencer element of the FIG. 5 control system, with FIG. **6**A providing the left panel, and FIG. **6**B the right panel, of 60 the block diagram.

# DETAILED DESCRIPTION OF A PREFERRED EMBODIMENT

Issues confronting a designer of a high capacity disk drive 65 including an embedded sector servo are perhaps best understood by considering the FIG. 1 plan view of a disk data

storage surface. A rotating storage disk 10, which may be 2.5 inches in diameter, or 1.8 inches in diameter, or larger or smaller, is formed of suitable substrate material such as metal or glass and is coated with e.g., a magnetic storage medium such as a thin film medium vacuum sputter deposited onto the substrate. The disk 10 defines a central opening 12 to enable a rotating hub securely to clamp the disk to a disk spindle. Between an inner landing zone area 14 and an outer peripheral zone 16, a data storage area of a multiplicity of concentric data tracks is defined. The tracks are arranged into e.g. eight data zones, 18, 20, 22, 24, 26, 28, 30 and 32, extending from a radially outermost zone 18 to a radially innermost zone 32. A system information zone 34 lies radially outwardly just beyond the outer zone 18, and a diagnostics and guard zone 36 lies just inside of the inner landing zone area 14. Since the number of magnetic storage domains varies directly in function of disk radius, the tracks of the outermost zone 18 will contain considerably more user data than can be contained in the tracks located at the innermost zone 32.

Outermost zone 18 includes e.g. 110 concentric data tracks, each having 58 data sectors, with a storage density of 43,334 bits per inch (BPI) (32,500 flux changes per inch encoded in 1,7 run length limited code). The raw data rate is 18.13 megabits per second, with a raw code rate of 27.20 Megahertz (MHz). Zone 20 includes e.g. 109 concentric data tracks, each having 56 data sectors per track, with a storage density of 44,269 bits per inch (32,202 flux changes per inch (FCI), a raw data rate of 17.45 megabits per second (MBPS) and a raw code rate of 26.18 MHz. Zone 22 includes e.g. 109 concentric data tracks, each having 52 data sectors per track, a storage density of 42,382 MBPS (31,787 FCI), a raw data rate of 15.69 MBPS and a raw code rate of 23.53 MHz. Zone 24 includes e.g. 109 data tracks, each having 52 sectors per 35 track, with a storage density of 45,334 MBPS (34,008 FCI) and a raw data rate of 15.69 MBPS and a raw code rate of 23.53 MHz. Zone 26 includes e.g. 109 concentric data tracks, each having 47 data sectors per track, a storage density of 45,900 BPI (34,425 FCI), a raw data rate of 14.77 MBPS and a raw code rate of 22.15 MHz. Zone 28 includes e.g. 108 concentric data tracks, each having 44 data sectors, a storage density of 47,008 BPI (35,256 FCI), a raw data rate of 14.00 MBPS and a raw code rate of 21.00 MHz. Zone 30 includes e.g. 108 concentric data tracks each having 41 data sectors, a storage density of 47,294 BPI (35,471 FCI), a raw data rate of 12.98 MBPS and a raw code rate of 19.43 MHz. Innermost data zone 32 includes e.g. 108 concentric data tracks each having 39 sectors per track, a storage density of 48,371 BPI (36,278 FCI), a raw data rate of 12.09 MBPS and a raw code rate of 18.13 MHz. The outer system zone **34** includes e.g. 14 concentric data tracks following e.g. the Zone 32 format, and the inner diagnostics zone 36 includes 1 track also following the Zone 32 format. A guard band 37 of four tracks lies immediately inside of the diagnostics zone 36. A landing zone LZ lies immediately inside of the guard band and diagnostics zone 36. The landing zone LZ is provided to implement a contact start-stop head flying arrangement for the disk drive.

FIG. 1 also depicts a series of radially extending, regular servo sectors 38. In this particular example, there are preferably 52 radial servo sectors 38 (shown diagrammatically as several narrow spokes in FIG. 1) equally spaced around the circumference of the disk 10. With disk rotation maintained at 16.667 milliseconds per revolution (3600 RPM), each servo sector takes up about 24.125 microseconds of the rotational interval. Other drive overhead includes the FIG. 3 data sector ID and data fields. While the number of data

sectors per track varies from zone to zone, it is apparent from inspection of FIG. 1 that the number of embedded servo sectors per track remains constant. In the present example the servo sectors 38 extend radially and are circumferentially equally spaced apart throughout the extent of the storage surface of the disk 10 so that the data transducer head 114 samples the embedded servo sectors 38 while reading any of the concentric tracks 10 defined on the data storage surface.

Each data sector is of a predetermined fixed storage 10 capacity or length (e.g. 512 bytes of user data per data sector); and, the density and data rates vary from data zone to data zone. Accordingly, it is intuitively apparent that the servo sectors 38 interrupt and split up at least some of the data sectors or fields, and this is in fact the case in the present 15 example. The servo sectors **38** are preferably recorded at a single data cell rate and with phase coherency from track to track with a conventional servo writing apparatus at the factory. A laser servo writer and head arm fixture suitable for use with the servo writer are described in commonly assigned U.S. Pat. No. 4,920,442, the disclosure of which is hereby incorporated herein by reference. A presently preferred servo sector pattern is described in copending U.S. patent applications Ser. Nos. 07/569,065 filed on Aug. 17, 1990, entitled "Edge Servo For Disk Drive Head Positioner, 25 now U.S. Pat. No. 5,170,299 and 07/710,172, filed Jun. 4, 1991 and entitled "Servo Data Recovery Circuit for Disk Drive Having Digital Embedded Sector Servo" abandoned in lieu of U.S. continuation application Ser. No. 08/180,096, filed on Jan. 11, 1994, and now U.S. Pat. No. 5,420,730, the 30 respective disclosures of which are hereby incorporated by reference. A very robust digital head position servo loop servo is realized, as described in the referenced U.S. Pat. No. 4,669,004 as further improved by the disclosures of the patent applications noted directly above. 35

As shown in FIG. 2, a data track 40 includes a data block 42 for storage of a predetermined amount of user data, such as 512 or 1024 bytes of user data, recorded serially by 1,7 RLL code bits in data field areas of the depicted track segment. The data block 42-1 is interrupted by several servo 40 sectors 38 which contain embedded servo information providing head position information to the disk drive via e.g. a thin film or metal-in-gap (MIG) data transducer head 114 (FIG. 4) which is positionable by a rotary voice coil actuator 108 radially with respect to the data surface in order to read 45 the data and servo information contained in the track 10, for example, as well as some or all of the other data tracks on the particular surface. The data block 42 includes an ID header 44 at the beginning of the data block and a data header 46 immediately preceding each data field segment 50 including the segment 42A following the ID header 44, and the segments 42B and 42C following interruption by servo sectors 38. The data header 46 is written at the same time that data is written to the segments 42, and a write splice therefore exists just before each data header 46.

As shown in greater detail in FIG. 3, the ID header 44 typically may include an ID preamble 50, an ID-type address mark 52, an ID field 54 containing three or four count bytes, a sector number byte, a head number byte, and a Reed Solomon error detection code. The data header 46 contains 60 a data preamble field 56 and a data address mark 58. The data header is immediately followed by a user data field 60 for storing the predetermined number of user data bytes, such as 512 bytes, for example. The user data field segment 60 is followed by an ECC field containing e.g. 12 ECC 65 syndrome remainder bytes. A pad field 62 follows the ECC field and separates a first data sector or block 42-0 from a

second data block 42-1, for example. Also, an ID/data header pad field 63 separates the ID header 44 from the data header 46 and contains the write splice.

The first data block 42-0 is shown in FIG. 3 as being uninterrupted throughout its circumferential extent. However, the block 42-1 is interrupted by a servo sector 38 and includes two data segments 42d and 42e, for example. Each split data segment, such as the segments 60-1 and 60-2 shown in the second sector 42-1 of FIG. 3, is preceded by a data header 46 including a data preamble field 56, and a data address mark 58. Immediately following the last data field segment 60-2 is the error correction field 62 containing the ECC remainder bytes.

In accordance with principles of the present invention, the count bytes, e.g. C1, C2 and C3, within the ID data field 54 are used to control automatic data block sequencing operations of a data sequencer 152 (FIG. 6). These count bytes enable the sequencer to determine automatically, and without microcontroller intervention, the layout of the particular. data sector 42 to be sequenced. In other words, the count bytes C1, C2 and C3 provide the respective byte lengths of each data segment 60 as interrupted by the fixed location servo sectors 38. In the FIG. 3 example the first data sector 42-0 is not split up into more than one data segment. Accordingly, count bytes C3, C2 and C1 are respectively 0, 0 and 7F (Hex, 127 decimal, the count bytes being divided by 4 to save register room in the sequencer 152). This pattern means that the first data segment 42F contains all of the data bytes, and there are no second (C2) or third (C3) segments.

A split data field example is encountered in data sector 42-1. Therein, the count bytes C3, C2 and C1 are respectively 0, 70, 01. This pattern of count bytes indicates that the first data segment 42D (C1) contains eight user bytes, and the second data segment 42E contains 504 bytes, and that there is no third segment in this particular example.

The count bytes are arranged in reverse order, so that they may be pushed onto a byte count stack 234 (FIG. 6) provided within the sequencer 152, as explained in greater detail hereinafter. The last count C1 for the first segment 42D, will be the first one popped off the stack 234 and loaded into a byte counter 236 of the sequencer 152 as the first segment of the particular data sector 42 is being read from or written to in real time. When the next segment is reached, the next count C2 for the second segment 42E is then popped off of the stack 234 and into the byte counter 236, and when the third segment is reached, the third count (C3) will be popped off of the stack 234 and loaded into the byte counter 236. This activity does not take place for byte count values of zero.

In this manner, the data sequencer 152 is able to reassemble automatically the data sectors 42 into unbroken continuous byte sequences which in the case of data reads from the disk are sent into a data block buffer preparatory to being transferred to the host. For incoming data blocks when data is being written to a storage surface of the disk 10, the sequencer 152 uses the count bytes in order to know how many bytes to sequence to the disk surface for each data sector data segment.

As already noted, each data sector 42 includes within the ID field 54 several error detection bytes which are used to verify the integrity of the information read back from the particular data ID field. These error detection code bytes (EDC) are preferably Reed Solomon syndrome remainder bytes which are coded from a code compatible with the error detection syndrome remainder bytes contained in the ECC fields 62. The EDC bytes as well as the ECC bytes are

checked in real time by an ECC circuit within the sequencer. A presently preferred EDC/ECC circuit is described in a commonly assigned, copending parent U.S. patent application, Ser. No. 07/650,791, filed on Feb. 1, 1991, the disclosure of which is hereby incorporated by reference.

Turning now to FIG. 4, a head and disk assembly 101 of an exemplary fixed disk drive data storage subsystem 100 is depicted in an approximate real size plan view. The data storage disk 10 may have any suitable diameter. While two and one half inches is presently preferred, larger disk 10 diameters, such as three and one half inches, five and one quarter inches, eight inches or larger, or smaller disk diameters, such as 1.8 inch, or smaller, are also clearly within the contemplation of the present invention. The data storage disk 10 is mounted upon a rotating spindle assembly 102 which is rotated by an in-spindle brushless DC spindle <sup>15</sup> motor 104 relative to a frame or base 106. Most preferably, motor bearings formed as a part of the spindle motor 104 are used to rotate the spindle assembly 102 relative to the base 106; and, the spindle motor itself is mounted to the base casting 106, as is conventional in miniature head and disk  $^{20}$ assemblies.

A motor driver circuit **107** (FIG. **5**) is provided to commutate e.g. the three-phase windings of the brushless motor **104**. Hall sensors, not shown, may be provided in order to determine the position of the rotary permanent magnet<sup>25</sup> element relative to the fixed windings and poles of the motor **104** and provide feedback control information to the motor driver circuit **107** in conventional fashion.

A plurality of e.g. thin film or MIG data transducer heads 30 114a and 114b are respectively associated with opposite major data storage surfaces of the at least one data storage disk 10. The data transducer heads 114 are preferably, although not necessarily, mounted to in-line aligned load beams 117 which in turn are attached to vertically aligned  $_{35}$ arms of an arm assembly 112 of a mass balanced rotary voice coil actuator 108. The heads 114a and 114b operate conventionally in a contact-start-stop relationship with respect to the data surface, and they "fly" above the surface during operations upon an air bearing as is conventional 40 with Winchester fixed disk technology, for example. During the assembly process, the heads 114 may be loaded onto the data storage disk in accordance with the teachings of commonly assigned U.S. patent application Ser. No. 07/610,306, now U.S. Pat. No. 5,027,241, the disclosure of which is 45incorporated herein by reference.

A head position actuator mechanism, most preferably a mass-balanced rotary voice coil actuator 108, includes a permanent magnet voice coil motor having an upper flux return plate 109 and a lower flux return plate securing e.g. 50 a pair of highly magnetic flat permanent magnets 110 of opposite magnetic polarity formed of a suitable material, such as a rare earth element such as nyodmium. A flat, wedge-shaped moving coil 111 defining an inner space a mass counterbalance and being integrally formed with or 55 otherwise mounted to a rotary actuator 112 moves in a magnetic gap formed between the upper flux return plate 109 and the permanent magnets 110. The rotary actuator 112 is journalled about bearings mounted to a post 113 secured to and extending upwardly from a floor wall of the base 106.  $_{60}$ To provide additional rigidity, the actuator post may also be secured to a top cover by a removable screw, should additional rigidity be needed or desired. A conventional elastomeric crash stop limits radial displacement of the rotary actuator 112.

As noted, the rotary actuator **112** includes a bearing assembly mounted to the base **106** via the actuator post **113** 

so that the rotary actuator 112 is free to rotate relative to the disk 10 over an arcuate radial locus of limited rotational displacement. Current passing through the coil 111 in one direction results in application of a rotary reaction force of the rotary actuator 112 in one direction, while current flow in reverse direction results in a rotary force being imparted to the rotary actuator **112** in an opposite direction. The rotary actuator 112 thus moves a ganged, substantially in-line head arm assembly across the surfaces of the disks within the drive. The head arm assembly includes a separate in-line load beam 117 for each data transducer head 114. In the present single storage disk example given in FIG. 4, the rotary actuator 112 supports e.g. two oppositely aligned data transducer heads 114, so that both surfaces of the disk 10 are used for storage and retrieval. If two or more spaced apart disks are included within the disk drive **100**, at least one data head 114 is provided for each surface and is commonly positioned with the other heads 114 by movement of the rotary actuator assembly 112.

An electromagnetic shipping latch engaging a protrusion formed e.g on the rear end of the coil molding **111** locks the head arm assembly to place the heads at the inner landing zone defined on the data surface. During a power-down sequence, power generated from kinetic energy in the spindle motor is directed into the coil **111** to move the head arm assembly to the landing zone, and is also directed into the latch to cause it to engage the actuator when the landing zone has been reached. Further details of a presently preferred electromagnetic shipping latch are set forth in commonly assigned, copending U.S. patent application Ser. No. 07/696,629 filed on May 7, 1991, and entitled "Bistable Magnetic/Electromagnetic Latch for Disk File Actuator", now U.S. Pat. No. 5,170,299, the disclosure of which is hereby incorporated by reference.

Magnetic flux transitions comprising both user data and servo sector data 38, are written by or read by the head 114 during data write or read operations. The data read by the head 114 is passed through a preamplifier circuit 120 (FIG. 5) which also provides head selection and write driving functions during data write operations. A conventionally available integrated circuit, such as the SSI 32R4610 four channel thin film head read/write device made by Silicon Systems, Inc., Tustin, Calif., or equivalent, is presently preferred for implementation of the circuit 120. The circuit 120 enables four separate heads 114 to be individually selected, and the circuit 120 is preferably mounted within a space defined within the head and disk assembly 101 upon a Mylar circuit substrate 122 which carries conduction traces leading to connections at an external printed circuit board carrying the other circuit elements of the disk drive 100. The circuit **120** is placed as close to the heads **114** as possible in order to reduce connection lead length, and to improve signal to noise ratios for each of the heads 114.

Turning now to the system block diagram provided in
FIG. 5, the generally vertical dashed line represents a printed circuit board 115 which carries all of the electronic circuit elements shown in FIG. 5 other than the preamplifier 120, and marks the demarcation between the head and disk assembly 101 and the circuit board 115. As shown in FIG.
5 analog flux transitions from a selected head 114 are amplified by a preamplifier within the circuit 120 and are then passed on to a circuit 124 including a pulse detector 126. Gain of the pulse detector circuit 126 is controlled by an AGC control circuit 128 also contained within the circuit 124. The pulse detector circuit 126 decodes the analog flux transitions into shaped digital edges or pulses representative of raw encoded data. The circuit 124 also includes a pre-

15

compensation circuit 130 for precompensating data to be written to the disk 10 during data writing operations, and a peak detector 132 for detecting peak amplitudes of servo bursts contained within the servo sectors 38 during track settling operations at the end of track seeking operations, and during track following operations.

The circuit 124 also includes a phase locked loop (PLL)134 for locking onto incoming data at a data rate predetermined for the particular data zone, as previously explained. A data frequency synthesizer 136 is provided for  $_{10}$ selectively generating the particular data transfer rate applicable within a track zone and supplies the synthesized frequency to the PLL 134. The circuit 124 is preferably contained within a single low power VLSI package, such as a type DP8491 made by National Semiconductor Corporation, or equivalent. The circuit 124, as is true with the entire system 100, preferably operates upon a single +5 volt power supply.

The data stream leaving the circuit 124 enters another circuit 140. The circuit 140 is also a single low power VLSI 20 package operating on a +5 V power supply, and it includes a servo data decoder circuit 142. The circuit 140 also includes a pulse width modulator 144 for sending strings of controlled duty cycle pulses generated from values supplied from the microcontroller 162 through a low pass filter 146 25 to control a servo driver circuit 148. The servo driver circuit 148 generates and applies drive currents to the coil 111 of the rotary actuator 108. Essentially, a digital servo is realized, as described in the referenced commonly assigned U.S. Pat. No. 4,669,004, as improved by the improvements described 30 in the referenced copending U.S. patent applications Ser. Nos. 07/569,065 filed on Aug. 17, 1990, entitled "Edge Servo For Disk Drive Head Positioner, now U.S. Pat. No. 5,170,299 and U.S. patent application Ser. No. 07/710,172 filed on Jun. 4, 1991, abandoned, continued by U.S. patent 35 application Ser. No. 08/180,096, filed on Jan. 11, 1994, and now U.S. Pat. No. 5,420,730 and entitled "Servo Data Recovery Circuit for Disk Drive Having Digital Embedded Sector Servo".

The servo data decoder circuit 142 preferably includes a 40 synchronizer for synchronizing incoming raw data to an internal clock, a first slave state machine for detecting servo sync and a unique pattern within a servo address mark field, and a second slave state machine for decoding data bits included within the servo address mark field, an index bit 45 field, and a Gray coded data field indicating the particular surface and track number. The servo data decoder circuit 142 also includes a sector timer which generates and puts out expected servo sector times within the circuit 140 based upon detection of each servo address mark, and a delay timer  $_{50}$ for timing delay periods associated with centerline burst fields included within each servo sector, and for putting out delay gates, the gates being used to control operation of the peak detector 132. Functional operations within the servo decoder circuit 142 are managed and supervised by a servo 55 master state machine which controls and monitors operations of the two slave state machines and determines detection of the servo address mark, an index mark, and collects the bits comprising the Gray coded track identification number. This number is passed onto the microcontroller 162  $_{60}$ which decodes it and determines head position during track seeking and settling operations of the drive.

The circuit 140 also includes an encoder/decoder 150 which decodes incoming data from e.g. 1,7 RLL code to NRZ format, and encodes data from the host in NRZ format 65 into e.g. 1,7 RLL code. The encoder/decoder 150 is substantially as described in a commonly assigned U.S. Pat. No.

4,675,652, the disclosure of which is hereby incorporated by reference. Following the encoder/decoder 150 is a data sequencer 152. The data sequencer is described hereinafter in greater detail in conjunction with FIGS. 6A and 6B. It basically functions to sequence data to and from the storage disk 10.

A buffer controller 154 controls operation of a buffer memory 166. While otherwise conventional, the buffer controller 154 includes a microcontroller buffer access circuit enabling the microcontroller 162 to write bytes to, and read bytes from, specified addresses in the buffer memory 166 in accordance with values supplied over the bus 160. An address control generates and applies addresses to the buffer memory 166 over a buffer address bus 172. A master control state machine generates the necessary clocks for clocking data blocks into and out of the buffer memory 166 and supplies those clocks to the address control. A bus multiplexer within the buffer controller 154 selects between data from a sequencer first-in, first-out buffer (FIFO) 196 (FIG. **6**B) and the microcontroller buffer access circuit.

The circuit 140 further includes a motor control circuit 156 which monitors disk rotational speed. The motor driver circuit **107** may provide a once-per-revolution index signal which may be compared against an internal timer, or the time between index marks provided by the servo control circuit 142 may be counted. Speed up (MTRUP) or slow down (MTRDN) signals are sent by the motor control circuit 156 to the motor driver 107. Finally, the circuit 140 includes a microprocessor interface 158 which connects directly to an internal control bus structure 160 over which control data and control address values are sent to and from a programmed digital microcontroller 162.

An internal data bus structure 164 connects the buffer controller 154 to a buffer memory 166 and also to an interface circuit 168. The interface circuit 168 includes bus drivers and other circuitry, such as a data FIFO buffer for buffering data flow from an external bus 170 and the buffer memory 166. The circuit 168 may also include a state machine for decoding bus level commands. Internal registers may be provided for receiving commands from the microcontroller 162.

The interface circuit 168, while conventional, is preferably configured to conform to the American National Standards Institute (ANSI) standard X3T9.2/82-2 Revision 17B at conformance level 2 for the small computer standard interface (SCSI), for example. It is controlled by a SCSI interface service routine executed by the microcontroller **162**. The interface **168** includes hardware for controlling all critical timing operations on the SCSI interface bus. Decoding of commands, time-outs, and other non-critical timing operations are performed by the SCSI service routine. The interface circuit 168 also includes on-board drivers for at least a single ended SCSI bus 170.

The interface circuit 168 includes an interface control block which connects to the bus 160 and enables the interface circuit 168 to appear to the microcontroller 162 as an array of directly addressable registers. By writing to these registers, the microcontroller 162 may arbitrate for the SCSI bus 170, select another device on the bus 170 and initiate data transfers. By reading these registers, the microcontroller 162 may determine the status of the interface circuit 168 and of the data transfer including error detection.

The buffer control 154 generates addresses for the buffer memory 166 and puts them out over an address bus 172. The microcontroller 162 puts out addresses over an address bus 174 to the microcontroller interface circuit 158. The microcontroller 162 directly addresses a program memory 178 over an address bus 176, and the circuit 158 latches and presents other ones of the address lines to the program memory 178 over an address bus 180.

Preferably although not necessarily, the programmed <sup>5</sup> microcontroller **162** is a single monolithic microcontroller such as the NEC 78322, or equivalent, operating in a two-phase time divided arrangement per servo sector wherein a first time interval upon the arrival of each servo sector is devoted to servo control operations for head <sup>10</sup> positioning, with a second and following time interval devoted to other tasks, including error correction operations, for example. An overview of this form of disk drive architecture is provided in the referenced U.S. Pat. No. 4,669,004. A hierarchical system for managing the tasks performed by <sup>15</sup> the microcontroller **162** during the second and following time interval is disclosed in the referenced U.S. Pat. No. 5,005,089.

An analog to digital converter **182** within the microcontroller **162** enables peak values detected by the peak detector **132** to be digitized and processed most preferably in accordance with a method described in the referenced co-pending U.S. patent application Ser. No. 07/569,065, reference to which is made for further particulars.

Further structural and functional details of the presently preferred disk drive architecture are found in a commonly assigned, copending U.S. patent application Ser. No. 07/710, 177, filed on Jun. 4, 1991, and entitled "Miniature Fixed Disk Drive" now U.S. Pat. No. 5,255,136 the disclosure of which is hereby incorporated herein by reference.

Turning now to FIGS. 6A and 6B, architectural details of the data sequencer 152 are given in greater structural detail. The data sequencer 152 includes an on-the-fly error correction circuit 190 as described in the referenced U.S. patent 35 application Ser. No. 07/650,791. In this regard, it should be noted that the sequencer 152 actually tests the syndrome remainder values supplied from the circuit 190 to see if the values are zero. Each of three data interleaves is tested separately, and the results are latched for each interleave (if 40 non-zero). This approach reduces to one-third the number of gates otherwise required to implement the sequencer's ECC test for zero logic tree.

The data sequencer 152 also includes a data field address mark detector 192 which receives incoming data directly 45 from the circuit 124. The address mark detector 192 looks for a sequence of high frequency flux transitions, and when such is detected, the PLL 134 is then locked onto the sequence and the recovered digital run length encoded data is checked for the presence of the address mark sequence. In 50 this regard, the address mark detector 192 monitors the data stream in order to detect a unique bit sequence which is not consistent with the 1,7 encoding rules and which is predetermined to represent an address mark. The address mark detector 102 is described in greater detail in a commonly 55 assigned, copending U.S. patent application Ser. No. 07/710, 065 filed Jun. 4, 1991 and entitled "Fault Tolerant RLL Data Sector Address Mark Decoder", now U.S. Pat. No. 5,231, 545, the disclosure thereof being expressly incorporated by reference herein. The address mark detector 102 generates 60 the byte clock signal BYTCLKA from the raw data stream as well as an address mark found (AMFOUND) control signal whenever a bit sequence representing an address mark is found in the raw data stream. The byte clock signal BYTCLKA is defined as the data in clock DIN divided by 65 twelve and synchronized with detection of the address mark by the address mark detector 102.

The 1,7 run length limited encoder/decoder 150 encodes and decodes serial data into and from a 1,7 run length limited (RLL) code, and the serializer/deserializer (SERDES) 194 contained within the circuit 150 but separately shown for clarity in FIG. 6, bundles and unbundles data bytes into and from serial 2 bit-by-2 bit format. A FIFO byte register 196 enables data bytes to be asynchronously transferred between the sequencer 152 and the external cache buffer memory array 166 which is clocked by an external crystal clock standard (as opposed to the BYTCLKA which is synchronized with the raw data stream read back from the disk).

A multiplexer **198** regulates bidirectional data flow through the serializer/deserializer **194** and encoder/decoder **150** so that ECC syndrome bytes generated by the ECC generator **190** may be appended to data blocks flowing to the storage surface of the disk **10**, and so that data values present on a writeable control store (WCS) bus **200** may also be sent to the disk for storage.

Reference data sector (i.e. physical sector and transducer head) identification bytes read from data ID fields are passed through a comparison multiplexer 202 to a comparison circuit 204. The comparison circuit 204 compares actual data sector identification bytes received from the SERDES 194 with the reference identification bytes held in a sector counter 206. If a correspondence exists, the desired sector location has been reached, and a Compare=0 control signal is put out by the comparison circuit 204 to a jump control multiplexer circuit 208.

The data sequencer 152 is most preferably implemented as a programmable state machine. Accordingly, a writeable control store (WCS) 210 is provided for containing code words which define progressively the various states of the sequencer 152. The WCS 210 stores sequencer control words which control all of the operational states of the sequencer 152. The WCS 210 may be loaded with information directly written by the microcontroller 162 with data supplied via a microcontroller data register 211 at WCS locations controlled by addresses decoded by a microcontroller address decoder 212.

The WCS 210 accepts control words which are e.g. 28 bits long. Each command line comprises a number of fields. One field is a 5-bit OPCODE field 250, a 2-bit count select field 252, a 3-bit primary control field 254, a 5-bit secondary control field 256, a 5-bit count field 258, and an 8-bit data field 260. Two of the fields, namely the secondary control field 256 and the bit count field 258 are dual purpose. During a count type command, as selected by a 00 value in the count select field 252, the field 256 contains the secondary control, and the field 258 contains a count specified in the command word. During a jump type command, selected by 01, 10 or 11 values in the count select field, the field 256 contains a jump control, and the field 258 contains a jump address. For both types of command words, the opcode, primary control and data fields 250, 254 and 260 are identical.

During one half of the BYTCLKA clock cycle, a multiplexer 214 enables direct access by the microcontroller 162 to the control store 210. During the other half of the BYTCLKA cycle, addresses from a sequence controller 216 are used to address the control store memory area 218. The sequence controller 216 includes a sequence control decoder block 220 which enables the controller 216 to jump to a plurality of predetermined states, a sequence address multiplexer 222 which selects between various possible addresses, a last address register 224 for holding the last sequencer address for application to the control store 210 via the multiplexer 214, and a writeable control store address +1

incrementer **226** which selectively feeds back the next address from the one held in the register **224** to the sequence address multiplexer **222**.

The sequence controller **216** is directly controlled by the jump control multiplexer **208** which generates a jump control signal when the value of the count select field **252** indicates a jump type control word. The jump control signal is generated from a plurality of logical inputs to the jump control multiplexer **206** as indicated in FIG. **6A**. The 28 bit wide writeable control store (WCS) data bus **200** directly communicates with the writeable control store **210** and enables the values held therein to circulate throughout the sequencer **152** along the paths shown in FIGS. **6A** and **6B**.

Specifically, an opcode bus **228** leads to an opcode decoder **230** which decodes each five bit opcode from the <sup>1</sup> opcode field **250** into a plurality of logical conditions on the control lines shown coming out of the opcode decoder **230**. For example, a PUSH SEL line extends from the opcode decoder to a push multiplexer **232** which enables e.g. data field count bytes **C3**, **C2** and **C1** to be pushed directly onto <sup>2</sup> the top of a four byte register stack **234**. A top of stack (TOS) bus and a next of stack (NOS) bus connect the stack **234** to a byte sequence counter **236** via a multiplexer **238** which also has the ability to load the sequence counter **236** with "1" values.

The byte sequence counter 236 maintains a present state byte count (remaining bytes within the present state of the sequencer 152). When the presently loaded byte count increments to zero, the end of a particular sequencer state is reached, and the sequence counter 236 puts out a SCNT=0 value to the sequence control decoder 220 so that a next sequencer state may then be invoked.

A control decoder 238 receives primary control value from the primary control field 254 and secondary control values from the secondary control field 256 (during a cour type command word as controlled by the count select value from the field 252). The control decoder 238 decodes thes values into specific logical control values which are put ou over the control lines shown coming out of the decoder 23 in FIG. 6B, including the write gate signal WRGATE and a initialize ECC signal IECC which directly control the ECC syndrome generator 190, for example. Push and pop signal for controlling the stack 234 are also put out from the control decoder 238. The control decoder 238 also puts out writ gate and read gate controls. Write gate is used to control dat writing to disk operations, whereas read gate is used to loc up the PLL 134 to data during read back operations from th disk.

A loop counter 240 is preset with a number of loops to b made during a particular data block transfer transactio (each loop nominally represents the states required to trans fer a data block), and generates a LOOPCNT=0 control value when the count reaches zero. This control valu signifying that the required number of data blocks has bee transferred is also provided to the jump control multiplexe 208. An index timeout counter 242 keeps track of th beginning of each track by generating an index timeou value INXCNT=0 which is used to control the sequence controller 216. A once per revolution raw index signal store in the first one of the servo sectors 38 is detected by the serv control circuit 142 and used to clock the index timeou counter 242. Other inputs to the sequence controller 216 at the jump value from the jump control multiplexer 208, th address mark found value AMFOUND from the address mark detector 192, and the byte sequence counter SCNT=0 value from the sequence counter 236.

The WCS 210 also includes a number of path-dedicated registers which lead via paths depicted in FIG. 6 to other elements within the sequencer 152. The following description sets forth a register address, a register name, and a description of the register:

	ADR	NAME	Description
10	A0	WCSOP	WCS Opcode and Count/Jump Select
10		This register allow	Register s the microcontroller 162 to write to
		and read from the	five bit opcode field 250 portion of
			-6) leading to the opcode bus 228,
			l read from a count/jump select field
15	Al	WCSCTL	WCS Control Register
		This register enabl	es the microcontroller 162 to write
			the primary control field 254 (bits
			dary control/jump control field 256 WCS 210 which is currently pointed
			troller WCS pointer register 212
20		(WCSADD).	
	A2		WCS Jump Address/Count Register es the microcontroller 162 to write
			he jump address field 256 and count
		field 258 (bits 0-5	) of the entry in the WCS 210 which
			t at by the microcontroller WCS
25	A3		WCS Window-Data Register 211
		This register enabl	es the microcontroller 162 to write
			he data field of the entry in the WCS
			onthy pointed at by the micro- pointer register 212. In addition,
			ster also causes the sequencer 152 to
30			try (as determined by previous
			three WCS window registers and by
			ster WCSADD, discussed below.
		While this update	may be performed while the
75			perating, modifying the WCS entry
55			resently executing may lead to un-
	<b>A</b> 4	WCSADD	Microcontroller WCS Pointer Register
		Bits 0-1 of this re	212 gister point to the address in the WCS
			modified by the next write by the
40		microcontroller 16	2 to the WCS window-data register
			Writing to this pointer register will
			er 152 to load the four WCS window current contents of the entry in the
		-	y this register. That entry may then
			difying the corresponding values in
45	45		registers. Sequencer WCS Pointer Register
	115	-	ister enables the microcontroller 162
			s of the last WCS entry executed by
	46		. Only bits 0–4 are active.
	AU		Top of Stack Register of Stack 234 is written by the microcontroller
50		0	alue will be loaded directly into the
			) of the sequencer stack 234. Writing
			s not push the value onto the stack a value to this register twice would
			of stack, and not the next of the
			the next of stack (NOS) position, a
55			ogram that performs a push function
			to the WCS and then executed by the
	A7	SECTNUM	Sector Number Register
			r register enables the microcontroller
<u> </u>			nt value into the sector counter 206, ource for comparison of ID field
00			pon the sequencer program. This re-
			nicrocontroller 162 to determine the
			a block transfer without rewriting the
			store 210. This register may be incre- encer program for multiple sector
65		transfers.	
55	A8	LOOPCNT	Loop Count Register
	20 25 30 35 40 45	10       A0         15       A1         20       A2         21       A3         30       A3         30       A4         40       A4         40       A5         50       A6         50       A7         60       A5	A0       WCSOP         10       This register allow and read from the the register (bits 2, and to write to and 252 (bits 0 and 1).         15       A1       WCSCTL         This register enable to and read from the second of the entry in the at by the microcond (WCSADD).       A2         20       A2       WCSJUMP         This register enable to and read from the field 258 (bits 0–5 is currently pointer register 21: pointer register 21: pointer register enable to and read from the and read from the aread from the writes to the other the write to this register enable to and read from the aread from the unite to this register enable to and read from the aread fr

LOOPCNT Loop Count Register Bit positions 0-6 of this register enable the micro-

-continued

ADR	NAME	Description		ADR	NAME	Description
		to set the value of the loop counter 240.				readback operation.
		the loop counter 240 naturally should	5			set, bit 2 inhibits the sequencer from en-
		in the sequencer 152 is halted or is in a				ffer memory interface. No bytes will be
	· · · · ·	lify sequence. In order to start a loop				respective of how the writeable control
		equest, the loop count modify request bit iencer Misc Command Register				is programmed. currently reserved for future commands.
		7 of the loop count register is a		AB	SEQSTAT	Sequencer Status Register
		d" read-only flag bit. Writing to this bit	10			ly register is read by the microcontroller
		ence. After the request bit is set, the	10			to obtain current status of the sequencer
		bit is monitored. Once the request bit is			152. Dit 0: Set with	150 ii
		ter 152 will not modify the loop counter discovery termination in the second se				nenever the sequencer 152 is running. es direction of sequencer data flow.
		a SEQMISC register at the request bit				of current command bit: No Buff"
		so long as the modify granted bit is set,				tes the syndrome latch of the ECC circuit
		oller 162 is free to modify the loop	15			, and contains the syndrome of the last
		vithout fear of a hardware conflict. The			error.	the support status of the "trianer in" sin
		162 must release the "modify granted" e data sector time, or the sequencer 152				tes present status of the "trigger in" pin. tes status of the sequencer internal flag bit.
		ount for the second sector, as only one				ed when the sequencer loop counter 240 is
	increment is sa				presently zero	
A9	WUSINXCNT	Write Unsafe Delay & Index Timeout	20			ed if the sequencer clock is currently off.
		Count Reg.		AC	SEQINT	Sequencer Interrupt Control/Status
		fe delay (bits 4–7) specifies the amount rite-gate is asserted that the write unsafe			The bits of th	Register his register monitor events in the sequencer
		gnored. This delay is to allow the write				he buffer controller 154. Each bit is set
		ect the effect of the write data pulses.				e signal it monitors is set. The bit will
		easured in byte steps. The index timeout	25			ven if the original signal is cleared, until
		) specifies the maximum number of index				e microcontroller 162. Clearing a bit
		v occur while the sequencer 152 is trying program. If the indicated number of				complished by writing a "1" to the corre- ation in this register. These events may be
	•	the sequencer will stop and set the				e an interrupt to the microcontroller 162
	index timeout i	lag in the sequencer error status register			over the sequ	encer interrupt line. Which events will
		h an occurrence generally indicates	30			pts is determined by programming the
AA	RGHIGCNT:	data ID header was not found. PLL High Gain Time Register.				terrupt mask register SEQMASK. The bits er are as follows:
		ontrols behavior of the interface between				the sequencer halts.
		52 and the read channel during reading				nen the ECC syndrome latch is closed. This
		e disk 10. When commanded into a high				surs when the sector just read has a non-
		PLL 134 within the read channel circuit occup to incoming data more rapidly.	35			ne (the data is incorrect). The ECC ch will now contain the syndrome of the
		ables shorter ID preamble fields and				he error and will hold this information
	therefore increa	ases the storage capacity for user data.			until the mic	rocontroller 162 opens the syndrome latch.
		to a high gain mode, the sequencer 152				the sequencer 152 to continue to process
		OW line low (thereby instructing high ned amount of time in steps of 8 code				ctors not having any errors.
		e times). This defined time is set into bits	40		microcontrol	
		HIGCNT register. When RDGATE is				nen a diagnostic signal selected by a
		the end of a data readback operation)				uxout function select register is asserted.
		ust lock back up to the reference clock. gain set to high gain mode at this time				then the sequencer flag bit is set. This bit e confused with the flag bit of the
	also.	and set to high gain mode at any time				atus register SEQSTAT.
		nel circuit 124 must reacquire AGC gain	45			it monitors the host transfer counter within
		o sector 38, as the particular data				controller 154 and is set whenever the
		be recorded at the same bit transfer rate ctor 38. While a delay to reacquire				austed. Thus, this bit is set at the end of
		then find the two byte high frequency				ransferred to the host via the interface.
		asserting RDGATE could be built into				ry controller 154. This bit is set when the
	the data formation	t, the extra delay has been avoided by	50		host transfer	counter is exhausted and the host loop
		post-servo read gate force (PWRGF)	20			ignal is asserted. This signal is asserted
		feature is enabled by setting bit 2 of the				e buffer 166 is configured for AT interface IFCTLN signal is asserted when the
		ister, discussed below, RDGATE is particular time interval after the servo				figured for SCSI interface.
		allow time for the AGC to settle. The				urrently used.
		by the PWRGF wait time is measured	55	AD	SEQMASK	Sequencer Interrupt Mask Register
		ode clocks (2/3 byte times). After the	55			in this register enables the corresponding
		set into bit positions 4–7 of this egister, the search for the data address				the interrupt status register to cause a terrupt by asserting the sequencer
		roceeds normally, as if two bytes of high				leading to the microcontroller 162.
		mble pattern had been found.			Bit 0: Not bi	
AB	SEQCMD	Sequencer Command Register	~~			Syndrome Latch closed.
		register is written to by the micro-	60			ncer Interrupt.
		to control the sequencer 152. et, bit 0 starts the sequencer. When			Bit 4: Seque	ncer Trigger. ncer Flag.
		tops the sequencer.			Bit 5: Host I	
	Bit 1 sets the	lirection of data flow. When set, data			Bit 6: Host I	
		buffer memory 166 to the disk 10,		A E	Bit 7: Not us	
	uuung a uisk (	lata write operation. When cleared, data	65	AE	SEQMISC	Sequencer Miscellaneous Command
		disk 10 to the buffer memory 166,				Register

20 -continued

-continued

ADR	NAME Description	<u></u>	Ā
	Setting a bit in this register (by writing a "1") prov various miscellaneous commands to the sequencer Bit 0: Forces the sequencer to halt. This will force	52. 5	
	sequencer interrupt, if enabled. Bit 1: Forces sequencer into the set state. Bit 2: Forces sequencer into the clear state.		
	Bit 3: Shuts down the sequencer section of the circ 140 to reduce power consumption.	10	
	Bit 4: Enables the Sequencer section of the circuit Bit 5: Sets loop count modify request bit and starts loop count modify sequence. See discussion above under Loop Count Register.		
	Bit 6: Clears loop count modify request bit. Bit 7: Forces the ECC syndrome latch open, or into	its 15	
AF	normally transparent state. SEQERROR Sequencer Error Status Register This register is used to monitor various error status signals in the sequencer 152. It is usually accessed the princentral law 162 access a balt to determine unit	by	
	the microcontroller 162 after a halt to determine when the sequencer has halted. The bit positions have the		
	following meanings: Bit 0: Set when the data address mark in the data f contains a special data pattern indicating that ECC		
	corrected data has been rewritten, for example. Bit 1. Set when the index timeout counter 242 exce		_
	the maximum number of indexes allowed for opera This bit is cleared by any write to the sequencer	tion. 25	
	command register SEQCMD. Bit 2: Set when the sequencer timed-out while sear		r t
	ing for a data address mark. The timeout limit is so the byte count field in the writeable control store	t by	t) a
	(WCS). This bit is cleared by any write to the sequencer command register SEQCMD.		t
	Bit 3: Set when the compare latch 204 is not equal	to 30	b c
	zero. The compare latch 204 is used to correctly identify data ID fields. This bit is cleared when a		t
	control word CALLL is written in the WCS. Bit 4: This bit is set to indicate that the last sector	read	-
	had a syndrome error. Syndrome detection is done an interleave basis. The bit is usually cleared at the		B
	start of a data sector by a control word CALLL		E
	written in the WCS. The bit is set if during the last byte of each interleave, that interleave's syndrome	re-	E
	mainder is not equal to zero. The ECC circuit 190 instructed to check the syndrome by the sequencer	is	Е
	when it executes the WDS, CRCS or ECCS opcod latch syndrome enable is set in the sequencer confi		
	uration register (Bit 4 of address WR-AF), the	_	
	syndrome latch is closed and the offending syndrom remainder is saved when the sequencer executes a	ne	E
	JSYN opcode. If the latch syndrome enable bit is r set, or the syndrome latch is already closed, the	ot 45	E
	sequencer 152 is ordinarily programmed to halt.		E
	Bit 5: This bit is set when the sequencer was halte because of an external or servo declared write faul		E
	This bit is cleared by any write to the sequencer command register SEQCMD.		E
	Bit 6: This bit is set if the FIFO 196 is in an over- or under-ran condition when the buffer controller 1		E
	accesses the FIFO. This bit is cleared by any write		
	the sequencer command register SEQCMD. Bit 7: This bit is set if there was a FIFO overrun c	r	E
	underrun when the sequencer 152 accesses the FIF 196. This bit is also cleared by any write to the		I I
	sequencer command register SEQCMD.	55	F
AF	SEQCONF Sequencer Configuration Regist The bit positions of this register control the operat		F
	configuration of the sequencer 152 and are written the microcontroller 162 during execution of initiali	by	
	tion program routines.	La-	

tion program routines. Bit 0: Not used.

Bit 1: When set, this bit causes the sequencer to compute and write a 2 byte error detection code within the data ID field during data formatting which is sufficient for disk drives not employing split data fields. When cleared, this bit causes the sequencer to compute and

22 -continued

	-continueu				
ADR	NAME	Description			
5	in the FIG. 3 Bit 2: When true after eac	byte error detection code as contemplated 3 split data field format. set, the sequencer will force RDGATE ch servo sector 38 has passed by. The RDGATE will be delayed by the wait			
0	time PWRGI Bit 3: When in the addres referenced co 07/710,861, 2 mark detecto	F contained in the RGHIGCNT register. set, this bit establishes fault tolerance with- ss mark detector 192 as described in the opending U.S. Pat. application Ser. No. now abandoned. When cleared, the address or 192 will not tolerate e.g. bit shift errors.			
5	syndrome lat halt when a thereby enab accordance v U.S. Pat. app	set, the sequencer 152 will use the tch within the ECC circuit 190 and will not non-zero syndrome remainder is detected, lling on-the-fly error correction in with the techniques described in copending plication Ser. No. 07/650,791 filed on			
0	Bit 5: When the read rate for writes. W				

The following registers contain non-zero syndrome remainder bytes which are latched by the syndrome latch of the ECC circuit **190**. In addition, two cross check bytes are also latched. The cross-check bytes enable the microcontroller **162** to determine the impact of a proposed correction

0 before the correction is actually made to the data block containing the detected error burst or bursts before correction is made.

	-						
35	B0	ECC	Latched Syndrome Remainder Interleave 0, Byte 0				
	B1	ECC	Latched Syndrome Remainder Interleave 0, Byte 1				
	B2	ECC	Latched Syndrome Remainder Interleave 0, Byte 2				
40	B3	ECC	Latched Syndrome Remainder Interleave 0, Byte 3				
	B4	ECC	Latched Syndrome Remainder Interleave 1, Byte 0				
	B5	ECC	Latched Syndrome Remainder Interleave 1, Byte 1				
45	B6	ECC	Latched Syndrome Remainder Interleave 1, Byte 2				
45	B7	ECC	Latched Syndrome Remainder Interleave 1, Byte 3				
	B8	ECC	Latched Syndrome Remainder Interleave 2, Byte 0				
	B9	ECC	Latched Syndrome Remainder Interleave 2, Byte 1				
50	BA	ECC	Latched Syndrome Remainder Interleave 2, Byte 2				
	BB	ECC	Latched Syndrome Remainder Interleave 2, Byte 3				
	BC	ECC	Latched Cross Check Byte 0				
	BD	ECC	Latched Cross Check Byte 1				
55	BE	BSTATE	Bytes Per State Register (for test purposes only)				
	BF	LSECT	Latched Sector Number Register				
		This register contains the contents of the sector number					
		register when the ECC syndrome latch was closed. In					
		other words, this register contains the sector number of					
		the particular data block determined by a non-zero					
60		syndrome remainder presently held in the ECC					
		syndrome latch to contain an error. This identification					
	enables the microcontroller 162 to locate the particular						
			in the buffer memory 166 and to carry out an ction on-the-fly.				
	-						

The following registers are associated with the buffer controller 154 and shed light upon its structure and function.

80 81

82 83

84

85

86

87

88 89

8A

8C

			the microcontroller address register. This register is used
HARLO Host Address Register, Low Byte			to fetch and replace an erroneous byte as a consequence
HARHI Host Address Register, High Byte	5		of the ECC operation carried out by the microcontroller
These two registers contain the address of the next byte		٩Ŋ	162 and the circuit 190, for example. MDR1 Microcontroller Data Register with
in the buffer memory 166 to be transferred to the host		8D	MDR1 Microcontroller Data Register with Automatic Increment
computer via the interface 168. The topmost bit of the			Writing this register will deposit the byte so written in
high byte register is not used, and is read as a zero.			the buffer memory 166 at the address specified by the
DARLO Disk Address Register, Low Byte	10		microcontroller address register. Accessing this register,
DARHI Disk Address Register, High Byte	10		whether reading or writing, or either byte of the micro-
These two registers point to the location in the buffer memory 166 of the next byte to be transferred to the disk			controller register will automatically cause the buffer
via the sequencer 162 and the read channel 124. The top-			controller 154 to prefetch the byte from the buffer
most bit of the high byte register is not used and is read			memory 166 specified by the address contained in the
as a zero.			microcontroller address register. Also, accessing this
MARLO Microcontroller Address Register, Low	15		register will cause the microcontroller address register
Byte	10	017	automatically to increment to the next byte address.
MARHI Microcontroller Address Register, High		8E	BCTL Buffer Controller Control Register
Byte			This register contains control bits for controlling opera- tion of the buffer controller 154. The bits are:
These two registers contain an address indicating the next			Bit 0: Enables the data path between the buffer memory
byte that the microcontroller data register will access.			166 and the disk 10.
The topmost bit of the high byte is not used and is read as	20		Bit 1: Enables the data path between the buffer memory
a "*".			166 and the host via the interface 168.
RLOAD Reload Register			Bit 2: Indicates the direction of data flowing from the
The host address registers HARLO and HARHI and the			hostbuffer channel. When set, indicates that data is flow-
data address registers DARLO and DARHI will be			ing from the host into the buffer 166.
loaded with the address contained in this register when a			Bit 3: When set enables rollover (and configures a virtual
roll-over occurs. This register follows the same conven- tion as the rollover register (discussed below) in that	25		ring buffer in the buffer memory 166)
only bits 6 through 1 are used, all lower bits are treated			Bits 4-7: Not used.
as zero, and the contents of this register correspond to		BF	BCFG Buffer Controller Configuration Register.
the high byte of the reload address.			This register enables the microcontroller program to con-
ROLL Roll-Over Register			figure the memory buffer controller 154.
The roll-over register specifies an address which			Bit 0: Enables the auto-write feature.
represents the top of a virtual ring buffer defined within	30		Bit 1: When asserted, specifies an IBM AT <sup>™</sup> type inter-
the buffer memory 166. The roll-over address comprises			face configuration at the interface 168.
bits 6 through 1 of this register, and the 9 lower bits are			Bit 2: When asserted, enables the buffer memory 166. There are several other registers contained within the
set to "1". Thus, the roll-over register appears to be the			circuit 140, and they are now briefly discussed.
high byte of the roll-over address, but the least significant		E0	MAP Microcontroller Memory Address Map
bit of this byte must be set to "1". When either the disk		20	Register
address registers DAR or the host address registers HAR	35		Bits 0–2: Controls the mapping of the microcontroller
reach the value contained in the roll-over register, and			address space C000H-DFFFH into address space for the
the roll-over feature is enabled for the host or data			program memory 178. These three bits control the most
channel, as appropriate, the corresponding address			significant three bits of the mapped address. Thus, writing
register is loaded with the contents of the reload register. Bits 7 and 0 of the roll-over register are not used.			"010" to these bits will map the microcontroller address
HXCLO Host Transfer Counter, Low Byte			C000H-DFFFH into the address range 4000H-5FFFH.
HXCHI Host Transfer Counter, High Byte	40		Bit 3: Writing a "1" to this bit position will cause a soft
These two registers together comprise a loadable counter			power on reset sequence to occur within the circuit 140.
containing the number of bytes to be transferred per			The power on reset condition will remain until a "0" is
block. Loading a value of "1" will cause two bytes to be			written to this bit position.
transferred. After reaching zero, this counter will auto-			Bits 4–5: This two-bit field is used to reset the hardware counters that divide down the clocks for the micro-
matically reload to the value initially loaded. When this	45		controller 162 and the interface circuit 168. The reset is
happens, the transfer will be halted if the loop count zero	45		caused by writing an "01" pattern to this field. These
signal is asserted. This host transfer counter is typically			time base counters will remain reset until the field is
preloaded with a value of 511, denoting transfer of 512			rewritten with a different pattern. Of course, writing an
byte blocks, and is preloaded when the auto-write signal			"01" pattern to this field will stop clocking at the micro-
is asserted. The auto-write signal only preloads this			controller 162 and it will not be able to rewrite this field.
counter and does not affect the reload value. AUTOWR Auto-Write Preload Register	50		Bit 6: The microcontroller write strobe MWRN is
AUTOWR Auto-Write Preload Register This register contains the value to preload into the host	50		normally narrowed to make data on the microcontroller
address registers in event of an auto-write. This register			bus 160 stable over both edges of the internal write
only uses bits 6 through 1, but it is adjusted to correspond			strobe. When this bit is set, this narrowing is bypassed
with the high byte of the host address register HARHI.			and the full MWRN strobe is used.
Because of this, bits 0 and 7 of HARHI are always pre-		E1	CRR Clock Rate Register
loaded to zero. This restricts preload boundaries to 512	55		In order for the disk drive 100 to employ a single quartz
byte boundaries in the buffer memory 166. For example,			crystal time standard, the circuit 140 generates a clock to
loading this register with 34H causes the first byte of a			operate the microcontroller 162 and another clock to run the interface circuit 168. This register controls the divider
block to be loaded into the buffer memory after an auto-			constant between the crystal frequency and the output
write to be placed at 3400H, the next byte at 3401H, etc.			clocks. The UPSEL field (bits 4–5) controls the micro-
MDR0 Microcontroller Data Register			controller clock rate (16, 8, 4, 1 MHz), and the IFPSEL
When the microcontroller 162 writes to this register, the	60		field (bits $0-1$ ) controls the present interface clock rate as
byte written will be transferred to the buffer memory			8, 6, 4, 0 MHz. To support power down options, an
166 at the address specified by the microcontroller			IFNSEL field (bits 2-3) has been included to control
address register. Accessing this register, either reading or			interface clocking rate after an auto-write as 8, 16, 4 or
writing, or either byte position of the microcontroller address registers will cause the buffer controller 154 to			0 MHz. This arrangement allows the interface circuit 168
prefetch the buffer memory byte at the location identified			to power down to a slow speed and still respond at the
by the microcontroller address register and store the	65	•	required rate to a write command over e.g. a bus such as
fetched value in this register. Accessing the micro-			the AT bus. Bit 6, when set, enables switching the inter-

controller data register will not automatically increment

# -continued

	face clock rate to the rate determined by IFNSEL when	
	an autowrite occurs.	
F0	MUXSELOUT Test Pin MUXOUT Function Select	
	This register controls the function of a diagnostic pin	
	MUXOUT of the circuit 140. The pin can be configured	
	as an input, enabling the sequencer 152 to monitor an	
	external signal. The pin can be configured as an output,	
	enabling external hardware to monitor internal signals	
	within the circuit 140. The functions are:	
	Bit 0: Trigger input to the sequencer.	
	Bits 1–3 Not currently used.	
	Bit 4: The pin puts out the index signal. This signal is	
	asserted when detected within the index servo sector and	
	is deasserted at the beginning of the next servo sector.	
	Bit 5: The pin puts out a true level during the time of	
	each servo sector 38.	
	Bit 6: The pin puts out the trigger signal from the	
	sequencer 152.	
	Bit 7: The pin puts out the commute input signal divided	
	by 12 from the spindle motor control circuit 107.	
Fl	MTRCONF Spindle Motor Configuration Register	
	This register controls configuration of the spindle motor	
	control circuit 156.	
	Bit 0: This bit must be set in order for the motor index	
	timer to run. The counter will be held reset if this bit is	
	cleared.	
	Bit 1: This bit enables the divide by 12 prescaler that	
	scales the commute signal before it is compared against	
	the index period counter 242. When this bit is set, the	
	commute pin is divided by 12.	
	Bit 2: When this bit is set, the tachometer signal	
	(COMUTE if 'Div $12' = 0$ , or COMUTE/12 if	
	'Div $12' = 1$ ) is OR'd with the SRVINT signal pin.	
	When this bit is clear, the pin is initially under the	
	control of the servo control circuit 142.	
	Bits 3–4: This field controls the width of the fixed period	
	of pump-down that the motor control puts out once per	
	revolution of the disk 10, as 32, 64, 128 or 256 clock	
	periods.	
	Bit 5: Writing a "1" to this bit position puts the index	
	period counter 242 into a test mode.	
	Bit 6: When this bit is set, the index period counter 242	
	runs off of the crystal clock at e.g. 32 MHz. Otherwise, it	
	runs off of the Fxtal/16 or 2 MHz.	
	Bit 7: This read only bit position puts out the state of the	
-	index period comparator	
F2	MTRCNTLO Spindle Motor Count, Low Byte	
F3	MTRCNTHI Spindle Motor Count, High Byte	
	This two byte register contains bits 0-15 of the spindle	
	motor count.	

The following table sets forth a description of the various signal lines shown entering and leaving the integrated circuit 45 140 in FIG. 5:

NAME	TYPE	DESCRIPTION
WRGATN	Out	Write gate out to pulse detector 126 and preamp 120.
WRUNSF	In	Write unsafe condition flag.
MUXOUT	Bi-Dir	Multiplexed test signal
PLLLOW	Out	Low Gain command for PLL 134
RDGATE	Out	Read Gate to PLL 134
RRC	IN	Read reference clock from PLL 134
RDDATA	IN	Synchronized read in data from PLL 134
WRDATA	OUT	RZ write data to pre-comp circuit in pulse detector 126
REFCLK	IN	Input from VCO of synthesizer 136 which is used during data writes to disk.
EARLY	OUT	Early precomp code to pre-comp circuit in pulse detector 126.
LATE	OUT	Late precomp code to pre-comp circuit in pulse detector 126.
RAWDAT	IN	Disk raw data read in from pulse detector 126.
<b>S[3:1]</b>	Out	S[3:1] control lines for peak detector 132.
AGCHLD	Out	AGC hold current gain level control for AGC circuit 128.

26	

		-continued
NAME	TYPE	DESCRIPTION
DISPD	Out	Discharge servo peak detectors in peak detector circuit 132.
BSTRDY	Out	Burst Readystarts analog to digital con- version process at a/d 182.
VCOFST	Out	Control from synthesizer control to cause synthesizer 136 to increase its frequency.
VCM1	Out	DAC output for PWM 144 data value "1" weighting value.
VCM32	Out	DAC output for PWM 144 data value "32" weighting value.
PORN	In	Power-on reset signal.
MAD [15:13]	In	Address bits 15, 14 and 13 for bus 174
MBUS[7:0]	Bi-Dir	Data bits $0-7$ of bus 160.
MRDN	In	Read strobe for bus 160.
MWRN	In	Write strobe for bus 160.
	In	
MALE		Bus 160 address latch enable.
SEQINT	Out	Interrupt from sequencer 152 to micro- controller 162.
SRVINT	Out	Interrupt from servo circuit 142 to micro- controller 162.
LA[15:13]	Out	Latched address output bits 15, 14 and 13 to ROM 156 over bus 180.
LA[7:0]	Out	Latched address output bits 7–0 to ROM 156 over bus 180
ROMCSN	Out	Chip select for ROM 178.
INFCS	Out	Interface circuit 168 chip select.
MTRUP	Out	Spindle motor accelerate up command from motor controller 156 to driver 107.
MTRDN	Out	Motor decelerate down command from motor controller 156 to driver 107.
COMUTE	In	Commutation signal from driver 107.
INFCTL	In	Interface control from interface circuit 168 (loop count zero, or autowrite)
REQN	In	Request for data bytes from interface circuit 168.
Ackn	Out	Acknowledge receipt of bytes from inter- face circuit 168.
BDT[7:0]	Bi-Dir	Buffer memory data bus 164 to buffer memory 166.
BAD[14:0]	Out	Buffer address bus 172 from memory controller 154 to buffer memory 166.
CSN	Out	Buffer memory chip select control line.
CEN	Out	Buffer memory 166 output enable line.
WRN	Out	Buffer memory 166 write enable line.
XTLIN	In	32 MHz crystal Oscillator input.
XTLOUT	Out	32 MHz crystal oscillator output from internal clock within circuit 140.
UPCLK	Out	Clock signal to microcontroller 162 (16 MHz nominal).
IFCLK	Out	Clock signal to interface circuit 168 (16 MHz or 8 MHz nominal).
		(10 mile of 0 mile noninial).

The following table sets forth count type commands which may be included in the primary control field 254 and secondary control field 256 and which are executed by the sequencer 152:

				COUNT-TYPE COMMANDS
	00	000	NOP	No operation
55	00	001	CWR	Clear write gate, read gate
	00	010	CWRE	Clear write gate, read gate, ECC
	00	011	CALLL	Clear write gate, read gate, initializes
				ECC to some known value, clears
				syndrome and compare latches.
	00	100	SUP	Set microcontroller interrupt bit
60	00	101	SOU	Set output to "1"
	00	110	ISDL	Increments sector number, decrements
				loop counter.
	00	111	SWG	Turns on write gate.
	01	000	IECC	Sets ECC/CRC to Initial state.
	01	001	CCS	Clears Compare and syndrome flip-flops
65	01	010	CTS	Loads "0" into top of stack of stack 234
05	01	011	POP	POP stack 234, filling top of stack with
				"0".

			-continued	
			COUNT-TYPE COMMANDS	
01	100	PUSH	Value in buffer pushed onto stack 234.	
01	101	RINX	Restart Index Timeout counter 242	5
01	110	EAB	Enable abort; operation may abort by microcontroller command or buffer error.	-
01	111	DAB	Disable abort	
10	000	SRG	Set read gate	
10	001	SERS	Clears Write Date Out.	
10	010	CERS	Normal Write Data Out.	10
10	011	COU	Clear output to "0".	10
10	100	SFLG	Set flag	
10	101	CFLG	Clear Flag	
10	110	CRG	Clear read gate	
10	111	FILF	Prefill of buffer FIFO 196 is enabled.	
11	000	FLSF	Any remaining data in FIFO is flushed.	15

The following table sets forth jump-type commands as indicated when a value other than "00" is present in the count select field 252. These commands are placed in the jump control field 256 and executed by the sequencer 152: 20

			JUMP-TYPE COMMANDS
0	XXXX	Jump if true	
1	XXXX	Jump if false	
х	0000	JMP	Jump Always; jump may be to next
			instruction for NOOP, or inverter for
			jump never.
x	0001	JTOS	Jump if Top of stack $= 0$
х	0010	JNOS	Jump if Next of stack $= 0$
x	0011	JLC	Jump if Loop count $= 0$ (operation
			complete)
х	0100	JSYN	Jump if ECC Syndrome flip-flop is
			clear
х	0101	JSC	Jump if both ECC Syndrome and
		-	Compare flip-flops are clear.
x	0110	JSCT	Jump if (syndrome = $0$ and
			compare = 0 and top of stack $<>0$ )
х	0111	JSCA	Jump if $(syndrome = 0 and com-$
			pare $= 0$ and special data address
			mark = 0).
х	1000	JFLG	Jump if $Flag = 0$
x	1001	JA	Jump if special address mark bit is
_			clear.
x	1010	JCMP	Jump if compare flip-flop = $0$ .
x	1011	JWDG	Jump if Servo (wedge) = $1$
x	1100	JINP	Jump on rising edge of input.
х	1101	JINX	Jump on rising edge of index.
X	111X	Reserved	1 0 0
			ids are placed in the primary control
			he count select field 252 is set to
		jump ("00").	
00	000	NOP	
00	001	CWR	Clear write gate, read gate, AME.
00	010	CWRE	Clear write gate, read gate, and
			initializes ECC to some known value
00	011	CALLL	Clear write gate, read gate, AME,
			sets ECC to some known value,
			clears syndrome and compare latches
00	100	SUP	Set microcontroller interrupt bit.
00	101	SOU	Set output to 1.
00	110	ISDL	Increments Sector number, Decre-
- •			ments Loop counter.
00	111	SWG	Turns on write gate.
	***	540	Tanto on write Bute.

As an aspect of the present invention the sequencer 152 may be programmed such that it need not be reprogrammed between read and write, thereby considerably speeding up  $^{60}$ its overall operational data block throughput. Accordingly, the following opcodes apply when the write gate is set, meaning that a write of one or more data blocks will be made to the data surface. Write gate set during a data ID header  $42\,$ 65 indicates that a data format operation is being performed. These opcodes are used when the sequencer 152 is causing

data to be written to the disk 10.

			OPCODES-WRITE GATE SET
5	0	AMIST	AME ID Search, Timeout; Write ID field address mark, set to two byte CRC mode.
	1	AMDST	AME Data Search, Timeout, Write data field
	2	AMIIT	address mark, set to 3 byte EDC mode. AME ID Immediate, Timeout; Write ID field
10	3	AMDIT	address mark, set to CRC mode. AME Data Immediate, timeout; Write Data field
	4	AMIS	address mark, set to ECC mode. AME ID Search; Write ID field address mark, set
	5	AMDS	to CRC mode. AME Data Search; Write Data Field address
15	6	AMII	mark, set to ECC mode. AME ID Immediate; Write ID field address mark,
15	7	AMDI	set to CRC mode. AME Data Immediate; Write data field address
	8	WD	mark, set to ECC mode. WCS Data; Data from the writeable control store
			is written to disk, data is not included within ECC/CRC.
20	9	WDE	WCS Data with ECC/CRC; Data from WCS is written to disk; data is included with ECC/CRC.
	10 11	WDC WDEC	WCS Data with compare; Same as WD. WCS Data with compare and ECC/CRC. Same as
	12	WDIR	WDE WCS Data, 1 count if read; Same as WCS data
25	12	WDS	(force 1 count if write gate = 0). WCS Data with Syndrome Check; Same as WCS
			data.
	16	BD	Buffer Data; Data from buffer 154 is written to disk, not included in ECC/CRC. Does not
30	17	BDE	generate FIFO request for last byte. Buffer Data with ECC/CRC. Data from buffer is
			written to disk. Does not generate FIFO request for last byte.
	18	BTS	Buffer to Top of Stack; Data from buffer 154 is written to top of stack 234 and to disk. Does not
35	19	BTSE	generate FIFO request for last byte. Buffer to Top of Stack with ECC/CRC; Data
		ι.	from buffer 154 is written to top of stack 234. Data is included within ECC/CRC. Does not
	20	BDX	generate FIFO request for last byte. Buffer data with extra byte; Data from the buffer
			154 is written to disk. Not included within ECC/ CRC. Generates a FIFO request for the last byte.
40	21	BDEX	Buffer data with ECC/CRC with extra byte; data from the buffer 154 is written to disk. Data is
			included within ECC/CRC. Generates a FIFO request from the last byte.
	22	BTSX	Buffer to Top of Stack with Extra Byte; Data from the buffer 154 is written to top of stack 234 and to
45	23	BTSEX	disk. Generates a FIFO request from the last byte. Buffer to Top of Stack with ECC/CRC and Extra
			Byte; Data from the buffer is written to the top of the stack 234 and to the disk. The data is included
			within ECC/CRC. A FIFO request is generated for the last byte.
50	24 25	TSD TSDE	Top of Stack Data; Not used. Top of Stack Data with ECC/CRC; Not used.
	26 27	SEC SECE	Sector; data from Sector written to disk. Sector with ECC/CRC; data from sector written
	28	ECC	to disk and includes ECC/CRC. ECC; "0"s shifted into the syndrome shift register,
55	20 29	CRC	ECC, o's sinite into the synthome sinit register, ECC written to disk; only used for data. CRC or Cross Check. "0"s shifted into syndrome.
	27	CILC	CRC written to disk if ID, crosscheck written to disk.
	30	ECCS	ECC with syndrome check; Same as ECC.
60	31	CRCS	CRC or Cross Check with syndrome check. Same as CRC.
	_		

The following opcodes are executed by the sequencer 152 when the write gate is cleared, i.e. during data readback from the disk. While the same opcodes are used, they have different functions during readback from disk than during write to disk.

20

25

30

#### OPCODES-WRITE GATE CLEARED

<ul> <li>AMIST AME ID Search, Timeout; look for ID field AM in search mode, use bps counter for timeout.</li> <li>AMDST AME Data Search, Timeout; look for data field AM in search mode, use bps counter for timeout.</li> <li>AMIT AME Data Immediate, Timeout; look for data field AM in immediate mode; use bps counter for timeout.</li> <li>AMDST AME Data Immediate, Timeout; look for data field AM in search mode, no timeout.</li> <li>AMDS AME Data Search; look for ID field AM in search mode, no timeout.</li> <li>AMIS AME Data Search; look for ID field AM in search mode, no timeout.</li> <li>AMI AME ID Immediate; look for ID field AM in mimmediate mode, no timeout.</li> <li>AMI AME ID Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field AM in immediate mode, no timeout.</li> <li>WD WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with CCMPare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDIF WCS Data with CC/CRC; data field AM in forces count to 1.</li> <li>WDE WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDIR WCS Data is compared with WCS data and used in ECC/CRC.</li> <li>WDIR WCS Data is count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data to Top of Stack, not used.</li> <li>BDTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDTSE Buffer Data to Top of Stack with ECC/CRC, not used.</li> <li>BDEX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BDEX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with Extra Byte; not u</li></ul>			OPCODES-WRITE GATE CLEARED
<ul> <li>AMDST AME Data Search, Timeout; look for data field AM in search mode, use bps counter for timeout.</li> <li>AMIT AME ID Immediate, Timeout; look for ID field AM in immediate mode; use bps counter for timeout.</li> <li>AMDT AME Data Immediate, Timeout; look for data field AM in immediate mode; use bps counter for timeout.</li> <li>AMIS AME Data Search; look for ID field AM in search mode, no timeout.</li> <li>AMIS AME Data Search; look for ID field AM in search mode, no timeout.</li> <li>AMI AME ID Immediate; look for ID field AM in search mode, no timeout.</li> <li>AMI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with CCC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare: Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDIR WCS Data with Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>WDIR WCS Data into WCS data field refer the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>WDS WCS data with ECC/CRC; with extra byte; same as BD.</li> <li>BUMFEr Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with EXTR Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and</li></ul>	0	AMIST	
<ul> <li>AMIIT AME ID Immediate, Timeout; look for ID field AM in immediate mode, use bps counter for timeout.</li> <li>AMDIT AME Data Immediate, Timeout; look for data field AM in immediate mode; use bps counter for timeout.</li> <li>AMIS AME ID Search; look for ID field AM in search mode, no timeout.</li> <li>AMIS AME Data Search; look for ID field AM in search mode, no timeout.</li> <li>AMDI AME Data Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDC WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDI WUES US Data with Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>WDI WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BDTS Buffer Data to Top of Stack with ECC/CRC.</li> <li>BUFS Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSK Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>SECE ECC; ECC read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>SECE Sector with SEC/CRC; data from disk if Data field.</li> <li>CCC CRC or Cross Check; CRC read from disk, if D fi</li></ul>	1	AMDST	AME Data Search, Timeout; look for data field
<ul> <li>out.</li> <li>AMDIT AME Data Immediate, Timeout; look for data field AM in immediate mode; use bps counter for timeout.</li> <li>AMIS AME ID Search; look for ID field AM in search mode, no timeout.</li> <li>AMDS AME Data Search; look for ID field AM in search mode, no timeout.</li> <li>AMDI AME ID Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with CCC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDE WCS Data a vith Compare; Data from WCS is compared with WCS data and used in ECC/CRC.</li> <li>WDIR WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data to Top of Stack; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Suffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Top of Stack Nath ECC/CRC, data from disk is read to the CC/CRC.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Suffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Suffer Data to Top of Stack with ECC/CRC.</li> <li>SECE Sector With ECC/CRC; data from disk, if ID field on tisk.</li> <li>SECE Sector Cross Check; CRC read from disk, if ID field, Cross check re</li></ul>	2	AMIIT	
<ul> <li>AMDIT AME Data Immediate, Timeout; look for data field AM in immediate mode; use bps counter for timeout.</li> <li>AMIS AME ID Search; look for ID field AM in search mode, no timeout.</li> <li>AMIS AME ID Immediate; look for data field AM in search mode, no timeout.</li> <li>AMID AME ID Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Search; look for data field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDR WCS Data i count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BDE Buffer Data to Top of Stack; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffe</li></ul>			•
<ul> <li>AMIS AME ID Search; look for ID field AM in search mode, no timeout.</li> <li>AMDS AME Data Search; look for data field AM in search mode, no timeout.</li> <li>AMII AME ID Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDE WCS Data with Compare; Data ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>WDIR WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BUFE Data at To Top of Stack with ECC/CRC; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC, and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>Top of Stack with ECC/CRC; data from disk is reame as BD.</li> <li>BTSE Suffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>Top of Stack with ECC/CRC; disk read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC.</li> <li>SECE Sector; data from disk.</li> <li>CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if ID field, Cross check; CC read from disk, check the syndrome, normally this is the last two bytes of the syndrome, normally thi</li></ul>	3	AMDIT	AME Data Immediate, Timeout; look for data field AM in immediate mode; use bps counter for
<ul> <li>AMDS AME Data Search; look for data field AM in search mode, no timeout.</li> <li>AMI AME ID Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDR WCS Data with Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>WDR WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BDE Buffer Data to Top of Stack, not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; and Earth BDE.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top of Stack with ECC/CRC.</li> <li>SECE Sector; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>SECE Sector; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>SECE Sector; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>SECE Sector wi</li></ul>	4	AMIS	AME ID Search; look for ID field AM in
<ul> <li>AMII AME ID Immediate; look for ID field AM in immediate mode, no timeout.</li> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDRC WCS Data usin Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>WDR WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data a the ECC/CRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>BUffer Data to Top of Stack, not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from disk if ID field, Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> </ul>	5	AMDS	AME Data Search; look for data field AM in
<ul> <li>AMDI AME Data Immediate; look for data field AM in immediate mode, no timeout.</li> <li>WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDE WCS Data with Compare; Data and USC data and used in ECC/CRC.</li> <li>WDIR WCS Data l count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data (Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BDE Buffer Data it COVCRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>BDE Buffer Data to Top of Stack, not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; and used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra BDE.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra BDE.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra BDE.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra BDE.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra BDE.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra BDE.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top of Stack with ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from disk if ID field, Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	6	AMII	AME ID Immediate; look for ID field AM in
<ul> <li>8 WD WCS Data; NOP, data in the WCS data field 260 is put into SERDES 194 so it may be pushed onto stack.</li> <li>9 WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>10 WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>11 WDEC WCS Data with Compare; and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>12 WD1R WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>14 WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>16 BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>17 BDE Buffer Data to Top of Stack; not used.</li> <li>19 BTSE Buffer Data to Top of Stack with ECC/CRC.</li> <li>18 BTS Buffer Data to Top of Stack with ECC/CRC.</li> <li>18 BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>21 BDEX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>23 BTSX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>24 TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>25 TSDE Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>26 SEC Sector; data from disk.</li> <li>27 SECE Sector with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk, if D field, Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	7	AMDI	AME Data Immediate; look for data field AM in
<ul> <li>stack.</li> <li>WDE WCS Data with ECC/CRC; Data from disk 10 used in ECC/CRC calculation.</li> <li>WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>WDEC WCS Data with Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>WD1R WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BUffer Data with ECC/CRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>BTS Buffer Data to Top of Stack; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>STSZ Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>STSD Top of Stack Nuth ECC/CRC; data from disk is a pushed on stack, included within ECC/CRC.</li> <li>SEC Sector; data from sector register compared with data read from disk.</li> <li>SECE Sector; data from sector register compared with data read from disk.</li> <li>SECE Sector; CCC read from disk if Data field.</li> <li>ECC ECC; ECC read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; data from disk if Data field.</li> <li>ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes</li></ul>	8	WD	WCS Data; NOP, data in the WCS data field 260
<ul> <li>10 WDC WCS Data with Compare; Data from WCS is compared with read data, no ECC/CRC.</li> <li>11 WDEC WCS Data with Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>12 WD1R WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>14 WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>16 BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>17 BDE Buffer Data to Top of Stack; not used.</li> <li>19 BTSE Buffer Data to Top of Stack; not used.</li> <li>19 BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>20 BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>21 BDEX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>22 BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>23 BTSEX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>24 TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>25 TSDE Top of Stack with ECC/CRC; disk read data pushed onto stack 234.</li> <li>26 SEC Sector; data from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check; CRC read from disk, if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> </ul>	9	WDE	stack. WCS Data with ECC/CRC; Data from disk 10
<ul> <li>11 WDEC WCS Data with Compare and ECC/CRC; disk data is compared with WCS data and used in ECC/CRC.</li> <li>12 WD1R WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>14 WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>16 BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>17 BDE Buffer Data with ECC/CRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>18 BTS Buffer Data to Top of Stack; not used.</li> <li>19 BTSE Buffer Data to Top of Stack with eXtra byte; same as BD.</li> <li>20 BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>21 BDEX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>22 BTSX Buffer Data to Top of Stack with EXTra Byte; not used.</li> <li>23 BTSEX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>24 TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>25 TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>26 SEC Sector; data from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk, if Data field.</li> <li>30 ECCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> </ul>	10	WDC	WCS Data with Compare; Data from WCS is
<ul> <li>ECC/CRC.</li> <li>WD1R WCS Data 1 count if read; Same as WCS Data but forces count to 1.</li> <li>WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BDE Buffer Data with ECC/CRC; data from disk is written to the buffer, included within ECC/CRC, not used.</li> <li>BTS Buffer Data to Top of Stack; not used.</li> <li>BDX Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BTSX Buffer Data to Top of Stack with EXTR Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with EXTR Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with EXTR Byte; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>TSDE Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; CRC read from disk, included within ECC/CRC.</li> <li>ECC CRC or Cross Check; CRC read from disk if DD field, Cross check read from disk. if Data field.</li> <li>ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	11	WDEC	WCS Data with Compare and ECC/CRC; disk
<ul> <li>14 WDS WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC state.</li> <li>16 BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>17 BDE Buffer Data with ECC/CRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>18 BTS Buffer Data to Top of Stack; not used.</li> <li>19 BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>20 BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>21 BDEX Buffer Data to Top of Stack with extra byte; same as BDE.</li> <li>22 BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>23 BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>24 TSD Top of Stack with ECC/CRC; disk read data pushed onto stack 234.</li> <li>25 TSDE Top of Stack with ECC/CRC; disk read data pushed on stack 234.</li> <li>26 SEC Sector; data from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>27 SECE Sector with ECC/CRC; data from disk if ID field, Cross Check; CRC read from disk if ID field, Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> </ul>	12	WD1R	ECC/CRC. WCS Data 1 count if read; Same as WCS Data but
<ul> <li>BD Buffer Data; Data from disk is sent to the buffer memory 166, not included in ECC/CRC.</li> <li>BDE Buffer Data with ECC/CRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>BTS Buffer Data to Top of Stack; not used.</li> <li>BTS Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BDE.</li> <li>BTSX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with EXC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>SECE ECC; ECC read from disk.</li> <li>CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>ECCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> </ul>	14	WDS	WCS data with Syndrome Check; looks at the syndrome, normally one byte state after the ECC
<ol> <li>BDE Buffer Data with ECC/CRC; data from disk is written to the buffer, included within ECC/CRC.</li> <li>BTS Buffer Data to Top of Stack; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDEX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BTSE Buffer Data to Top of Stack with extra byte; same as BDE.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top of Stack with ECC/CRC and Extra Byte; not used.</li> <li>TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>SECE Sector; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>ECC ECC; ECC read from disk.</li> <li>CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> </ol>	16	BD	Buffer Data; Data from disk is sent to the buffer
<ol> <li>BTS Buffer Data to Top of Stack; not used.</li> <li>BTSE Buffer Data to Top of Stack with ECC/CRC; not used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDEX Buffer Data to Top of Stack with extra byte; same as BDE.</li> <li>BTSX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>SEC Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC.</li> <li>ECC ECC; ECC read from disk, included within ECC/CRC.</li> <li>ECC ECC; ECC read from disk.</li> <li>CRCS CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ol>	17	BDE	Buffer Data with ECC/CRC; data from disk is
<ul> <li>used.</li> <li>BDX Buffer Data to Top of Stack with extra byte; same as BD.</li> <li>BDEX Buffer Data with ECC/CRC with extra byte; same as BDE.</li> <li>BTSX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack 234.</li> <li>SECE Sector; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>ECC ECC; ECC read from disk.</li> <li>CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>CRCS CRC CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>			Buffer Data to Top of Stack; not used.
<ul> <li>as BD.</li> <li>21 BDEX Buffer Data with ECC/CRC with extra byte; same as BDE.</li> <li>22 BTSX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>23 BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>24 TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>25 TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>26 SEC Sector; data from sector register compared with data read from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>			used.
<ul> <li>same as BDE.</li> <li>22 BTSX Buffer Data to Top of Stack with Extra Byte; not used.</li> <li>23 BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>24 TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>25 TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>26 SEC Sector; data from sector register compared with data read from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>			as BD.
<ul> <li>used.</li> <li>BTSEX Buffer Data to Top Of Stack with ECC/CRC and Extra Byte; not used.</li> <li>TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>SEC Sector; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>ECC ECC; ECC read from disk.</li> <li>ECC CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>			same as BDE.
<ul> <li>Extra Byte; not used.</li> <li>TSD Top of Stack Data; Disk Read data pushed onto stack 234.</li> <li>TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>SEC Sector; data from sector register compared with data read from disk.</li> <li>SECE Sector with ECC/CRC; data from sector register compared with ata read from disk, included within ECC/CRC.</li> <li>ECC ECC; ECC read from disk.</li> <li>CRC GRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> <li>CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>			used.
<ul> <li>stack 234.</li> <li>25 TSDE Top of Stack with ECC/CRC; disk read data pushed on stack, included within ECC/CRC.</li> <li>26 SEC Sector; data from sector register compared with data read from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	23		Extra Byte; not used.
<ul> <li>pushed on stack, included within ECC/CRC.</li> <li>26 SEC Sector; data from sector register compared with data read from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	24	TSD	
<ul> <li>26 SEC Sector; data from sector register compared with data read from disk.</li> <li>27 SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	25	TSDE	
<ol> <li>SECE Sector with ECC/CRC; data from sector register compared with data read from disk, included within ECC/CRC.</li> <li>ECC ECC; ECC read from disk.</li> <li>CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ol>	26	SEC	Sector; data from sector register compared with
<ul> <li>28 ECC ECC; ECC read from disk.</li> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	27	SECE	Sector with ECC/CRC; data from sector register compared with data read from disk, included
<ul> <li>29 CRC CRC or Cross Check; CRC read from disk if ID field, Cross check read from disk if Data field.</li> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>	20	FCC	
<ul> <li>30 ECCS ECC with syndrome check; ECC read from disk, check the syndrome, normally this is the last two bytes of ECC.</li> <li>31 CRCS CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of</li> </ul>			CRC or Cross Check; CRC read from disk if ID
31 CRCS       CRC or Cross Check; CRC read from disk, check the syndrome, normally this is the last two bytes of	30	ECCS	ECC with syndrome check; ECC read from disk,
the syndrome, normally this is the last two bytes of			
	31	CRCS	the syndrome, normally this is the last two bytes of
			UNU.

30

The following command line sequence example illustrates operation of the drive **100** with split data fields, for both data block writing and data block reading operations without reprogramming the WCS **210**. The writeable control store **210** has its random access memory area written with a sequence such as is exemplified by the following example, and the jump control multiplexer **208**, and the sequence

10 controller **216** cause each instruction word to be loaded and executed on a control word by control word basis. Importantly, there is no need to reload the WCS for either a split data field, or when switching from reading to writing. The

<sup>15</sup> state of the write gate controls whether reading or writing will be accomplished.

35

40

45

50

55

			R	EAD-WRITE WI	ITH SPLIT DA	TA FIELI	DS
	250	252	254	256	258	260	
ADR	OP	CNT	CTRL	JP/CTRL	ADD/CTRL	DATA	DESCRIPTION
0	AMIS	WCT	CALLL	EAB	0		ID AM, abort ena.
1	TSDE	WCT	NOP	CTS	2		Fill count stack
2	SECE	WCT	NOP	NOP	Õ		Compare sector
3	WDEC	WCT	NOP	NOP	0		head compare head
4	CRC	WCT	NOP	NOP	Ō	_	Do EDC, syndrome not ready yet.
5	CRCS	WCT	NOP	NOP	1	_	Do EDC, set synd address register
6	WDS	CT1	CWRE	+JSCT	12		Start Sync immed.
7	WD	CT1	NOP	–JSC	0	_	look for next ID
8	WD1R	WCT	NOP	POP	1	PAD	PAD-POP stack
9	WD	CT1	CWR	–JWDG	9		Wait for servo sector 38
10	WD	CT1	SWG	JWDG	10	SYNC	Preload encoder
11	WD	WCT	NOP	NOP	1	SYNC	AGC rcovry after servo sector 38
12	WDIR	WCT	SWG	DAB	7	SYNC	Sync Field (no abort)
13	WD	WCT	NOP	SRG	0	71H	First half of AM (for write)
14	AMDIT	WCT	NOP	FFFL	12	A3H	Second half of Am
15	BDE	TSCT	NOP	–JNOS	8	_	Actual data
16	CRC	WCT	NOP	NOP	1	_	Cross Check
17	ECC	WCT	NOP	NOP	9	_	ECC
18	ECCS	WCT	NOP	NOP	1	_	ECC check 1st w/o interleaves
19	WDS	CT1	SUP	-JSCA	31	PAD	Bad syndrome? AM? Special AM?
20	WD	CTI	ISDL	–JLC	0	PAD	Done?
21	WD	1 <b>C</b> T	CWR	+JMP	31	—	Done!

Another command line sequence example below illustrates a disk-data-format operation with split data fields. In this example the buffer contains the counts, head and sector numbers to be written to the disk **10** and also a 1-byte non-zero number if a wait-for-sector is not to be done before <sup>30</sup> the next ID. The last one of these must be zero.

are by way of illustration only and should not be construed as limiting the scope of the present invention which is more particularly pointed out by the following claims.

What is claimed is: U.S. patent application Ser. No. 07/710,861, now abandoned.

1. A programmable data sequencer within a disk drive

0	WD	CT1	CALLL	-JINX	0	_	Wait for beginning index.
1	WD	CT1	CWR	–JWDG	1		Wait for servo sector before ID
2	WD	CT1	SWG	JWDG	2	SYNC	Preload.
3	WD	WCT	NOP	ENAB	0	SYNC	Sync Field (enable abort)
4	WD	CT1	NOP	JMP	6	SYNC	Jump over write/read recovery.
5	WD	WCT	NOP	NOP	0	PAD	Write to read recovery if no servo sector before ID.
6	WD	WCT	NOP	IECC	8	SYNC	Sync field.
7	WD	WCT	NOP	CTS	0	71H	First byte of AM.
8	AMIS	WCT	NOP	FFFL	0	E8H	ID address mark
9	BTSEX	WCT	NOP	NOP	2	_	Fill count stack from buffer and write it. Fetch byte
							for next state
10	BDEX	WCT	NOP	NOP	2	_	Write Head, Sector, Fetch Extra Byte to mark wait
							for servo wedge before ID
11	CRC	WCT	NOP	NOP	2	PAD	Write EDC/CRC (never check syndrome)
12	WD	WCT	NCP	NOP	0	PAD	Extra pad byte.
13	WD	CT1	NOP	–JTS	17	PAD	Start Sync immed.
14	WD	CT1	CWR	–JWDG	14	·	Wait for servo
15	WD	CT1	SWR	+JWDG	15	PAD	Preload, wait for servo sector end.
16	WD	WCT	NOP	POP	1	PAD	AGC recovery field.
17	WD	WCT	NOP	NOP	12	PAD	SYNC + AM + PAD counts.
18	WD	TSCT	NOP	-JNS	14	PAD	Actual Data field.
19	WD	WCT	NOP	PUSH	12	PAD	Write ECC syndrome remainder bytes.
20	WD	CT1	ISDL	–JTS	5	PAD	Go to write/read recovery field, no servo before ID.
21	WDÍ	CT1	CWR	-JLC	1	_	Done?
22	WD	CT1	NOP	+JMP	31	—	Done!

The microfiche appendix accompanying the parent U.S. patent application Ser. No. 07/710,861, now abandoned, sets forth in greater detail electrical circuit schematics for the sequencer circuit **152** and also control program routines for  $_{60}$  execution by the microcontroller **162**.

To those skilled in the art, many changes and modifications will be readily apparent from consideration of the foregoing description of a preferred embodiment without departure from the spirit of the present invention, the scope 65 thereof being more particularly pointed out by the following claims. The descriptions herein and the disclosures hereof

including a rotating data storage disk defining a multiplicity of concentric data tracks, at least one of said data tracks including a sequence of fixed capacity data fields which are split into fractional field segments by intervening embedded servo sectors, each one of said data fields being preceded by a data field identification header including plural user byte count values, each one of the plurality of user byte count values indicating a user byte count storage capacity of a corresponding fractional field segment, the disk drive further including a data transducer controllably positioned by a servo head position control loop using information from

the embedded servo sectors to pass over said at least one of said data tracks for reading a data field identification header and data field segments of each data field, and a buffer memory means for temporarily storing a fixed length user data block read from or written to the user data field; the programmable data sequencer connected to a read channel including the data transducer and to the buffer memory means, and comprising:

- control means for controlling transfer of a user data block between the buffer memory means of said disk drive and the segments of the data field and including a loadable byte sequence counter means for receiving and counting a present user byte count value as the data transducer passes over a corresponding contiguous segment,
- stack memory means for receiving from the read channel and for holding each user byte count value associated with the corresponding contiguous segment so that the storage capacity of user bytes of said segment is determined directly by said sequencer from said user byte count value, and 20
- stack memory control means for pushing each user byte count value being received from the read channel onto the stack memory means as the data transducer passes over the data field identification header, and for popping each user byte count value from the stack memory<sup>25</sup> means to the loadable byte sequence counter means as the data transducer approaches the corresponding contiguous segment.

2. The programmable data sequencer set forth in claim 1 wherein said control means comprises: 30

- writeable control store means including random access memory means directly addressable by a programmed digital microcontroller means of said disk drive for writing sequences of control patterns, there being dual function control patterns such that a single sequence of control patterns may be written for controlling states of said programmable data sequencer during both data read operations and data write operations to and from the rotating data storage disk and the buffer memory means, and
- control pattern decoding means for decoding the control patterns into functional values for controlling operations within the programmable data sequencer.

3. The programmable data sequencer set forth in claim  $2_{45}$  wherein the control patterns include an opcode field control pattern, a count select field control pattern, a count of field control pattern, a count field control pattern, a count field control pattern, and a data field control pattern, a

- and wherein the control pattern decoding means includes: 50 opcode decoding means for decoding values compris
  - ing an opcode of a control pattern sequence,
  - jump field decoding means for decoding values comprising a jump field control pattern of said sequence, control field decoding means for decoding the control 55
  - field control pattern of said sequence, counting means responsive to said count field control
  - pattern of said sequence,
  - data decoding means responsive to said data field control pattern of said sequence, 60
- the count select field pattern for controlling selection between a command operational mode and a jump operational mode for said sequence.

4. The programmable data sequencer set forth in claim 3 wherein at least one control pattern sequence includes a dual 65 purpose control pattern whose purpose is selected by the count select field pattern.

5. The programmable data sequencer set forth in claim 4 including structure responsive to at least two types of control sequences, both types including opcode, data and primary control fields, one type being where a count is required and including a secondary control word field and a count field, and another type being where a jump is required and having a count field of either a one, a top of stack value, and a next of stack value; a jump field and a jump address field.

6. The programmable data sequencer set forth in claim 5 wherein the jump field occupies a same space in the writeable control store means as occupied by the secondary control word field, and wherein the jump address field occupies a same space in the writeable control store means as occupied by the count field, and wherein the structure uses the count select field pattern to determine one of the at least two types of control sequence.

7. The programmable data sequencer set forth in claim 1 wherein said control means comprises:

- writeable control store means including random access memory means directly addressable by a programmed digital microcontroller means of said disk drive for writing sequences of control patterns, there being a single sequence written for controlling states of said programmable data sequencer during data read and data write operations to and from the data storage disk and the buffer memory means,
- the control patterns including an opcode field control pattern, a count select field control pattern, a control field control pattern, a jump field control pattern, a count field control pattern, and a data field control pattern,
- opcode decoding means for decoding values comprising an opcode of a sequence,
- jump field decoding means for decoding values comprising at least one of a count select field control pattern and a jump field control pattern,
- control field decoding means for decoding the control field control pattern,
- counting means responsive to said count field control pattern, and
- data decoding means responsive to said data field control pattern.

8. The programmable data sequencer set forth in claim 1 wherein the embedded servo sectors comprise a series of circumferentially spaced apart, radially extending servo sectors, each servo sector being prerecorded with flux transition patterns defining a servo address mark, a servo sector identification number and servo centerline information, the flux transition patterns defining the servo sector identification number and the servo centerline information being converted by the disk drive into digital numbers representing head position relative to one of said concentric data tracks containing said servo sector, said concentric track zones, each zone having a user data transfer rate related to radial offset of said zone from a center of rotation of the data storage disk.

9. The programmable data sequencer set forth in claim 1 wherein said disk drive includes a programmed microcontroller means for controlling said programmable data sequencer and said buffer memory means and wherein the control means includes a loadable sector counter means which is directly loadable by the programmed microcontroller means of said disk drive and wherein the sector counter means is responsive to a data clock means for counting a preset number of data bytes comprising a data field.

10. The programmable data sequencer set forth in claim 2 wherein the disk drive includes a programmed microcontroller means for controlling said programmable data sequencer and said buffer memory means and wherein the control means includes loadable loop counter means directly 5 loadable by said programmed microcontroller means and responsive to a data clock means for counting a present number of data byte clock periods corresponding to a loop established within sequences of said control patterns.

11. The programmable data sequencer set forth in claim 2 10 wherein the disk drive includes a programmed microcontroller means for controlling said programmable data sequencer and said buffer memory means and further comprising loadable sector counter means directly loadable by said programmed microcontroller means and responsive to a 15 data clock means for counting a preset number of data bytes comprising a data field, and loadable loop counter means directly loadable by said programmed microcontroller means and responsive to said data clock means for counting a present number of data byte clock periods corresponding 20 to a loop established within sequences of said control patterns, said control field decoding means for decoding the control field control pattern and generating said data clock means for clocking said sector counter means and said loop counter means.

**12.** A disk drive comprising a rotating magnetic recording disk having a data storage surface defining a multiplicity of concentric data tracks, at least one track defining a plurality of fixed-block-length user data block storage locations, the

fixed-block length user data block storage locations being divided up into a plurality of irregular byte-length user data segments, each fixed block length user data block storage location having a header field including a plurality of count values, each count value comprising a count of bytes within a corresponding irregular byte-length user data segment, means for reading and transferring user bytes within the at least one track including segments to temporary storage and the count values within header fields to a count value memory stack, count value memory stack control circuitry for pushing the count values onto the count value memory stack as the count values are transferred from a header field, and for popping a count value from the count value memory stack into a segment counter as a corresponding irregular byte-length user data segment is to be read, the segment counter being decremented to zero thereby to determine the irregular byte-length of the user data segment as user bytes from the user data segment are transfered to temporary storage.

13. The disk drive set forth in claim 12 wherein the count values for segments comprising a fixed-block length user data block are pushed onto the count value memory stack in reverse order of occurrence of the segments, so that a count value for a segment first encountered by the means for reading and transferring is at a top of stack location within the count value memory stack and is popped into the segment counter.

\* \* \* \* \*